RF Test Report

For

Applicant Name:	**Shenzhen annengxin technology co.,ltd**
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China
EUT Name:	Smart Switch
Brand Name:	N/A
Model Number:	AN-WDS01
Series Model Number:	Refer to section 2

Issued By

Company name:	**BTF Testing Lab (Shenzhen) Co., Ltd.**
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Report number:	BTF230228R00101
Test standards:	FCC CFR Title 47 Part 15 Subpart C (§15.247)
FCC ID:	2BAF7-ANWDS01
Test conclusion:	Pass
Date of sample receipt:	2025-04-16
Test date:	2025-04-16 to 2025-05-06
Date of issue:	2025-05-08
Test by:	Sean He / Tester
Prepared by:	Chris Liu/ Project engineer
Approved by:	Olic Huang/EMC manager

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Revision History		
Version	Issue Date	Revisions Content
R_V0	2025-05-08	Original
Note: Once the revision has been made, then previous versions reports are invalid.		

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1 Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130
FCC Registration Number:	518915
Designation Number:	CN1409

1.3 Announcement

(1) The test report reference to the report template version v0.
(2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
(3) The test report is invalid if there is any evidence and/or falsification.
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2 Product Information

2.1 Application Information

Company Name:	Shenzhen annengxin technology co.,ltd
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China

2.2 Manufacturer Information

Company Name:	Shenzhen annengxin technology co.,ltd
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China

2.3 Factory Information

Company Name:	Shenzhen annengxin technology co.,ltd
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China

2.4 General Description of Equipment under Test (EUT)

EUT Name:	Smart Switch
Test Model Number:	AN-WDS01
Series Model Number:	AN-WS01, AN-WS01L, AN-WCS01, AN-WFS01, AN-WFLS01, AN-WHS01, AN-WHS02, AN-WS02, AN-WS02L, AN-WS03, AN-WS03L, AN-WS04, AN-WS04L
Description of Model name differentiation:	Only the model name is different, everything else is the same.
Rating:	Voltage:AC 100-240v 50~60hz Output:400W

2.5 Technical Information

Power Supply:	AC100-240V 10A
Operation Frequency:	2402MHz to 2480MHz
Number of Channels:	79
Modulation Type:	GFSK, π/4 DQPSK, 8DPSK
Antenna Type:	PCB ANT
Antenna Gain#:	1.3dBi
Note: #: The antenna gain provided by the applicant, and the laboratory will not be responsible for the accumulated calculation results which covers the information provided by the applicant.	
Bluetooth Version:	5.0

Channel list:

Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency
0	2402MHz	20	2422MHz	40	2442MHz	60	2462MHz
1	2403MHz	21	2423MHz	41	2443MHz	61	2463MHz
…	…	…	…	…	…	…	…
10	2412MHz	30	2432MHz	50	2452MHz	70	2472MHz
11	2413MHz	31	2433MHz	51	2453MHz	71	2473MHz
…	…	…	…	…	…	…	…
18	2420MHz	38	2440MHz	58	2460MHz	78	2480MHz
19	2421MHz	39	2441MHz	59	2461MHz	-	
Remark: Channel 0, 39 & 78 have been tested for GFSK, π/4-DQPSK, 8DPSK modulation mode.							

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3 Summary of Test Results

3.1 Test Standards

Identity	Document Title
FCC CFR Title 47 Part 15 Subpart C (§15.247)	Intentional Radiators - Operation within the bands 902–928 MHz, 2400–2483.5 MHz, and 5725–5850 MHz.
ANSI C63.10-2020	American National Standard of Procedures for Compliance Testing of Unlicensed Wireless Devices
KDB 558074 D01 15.247 Meas Guidance v05r02	Guidance for Compliance Measurements on Digital Transmission System, Frequency Hopping Spread Spectrum System, and Hybrid System Devices Operating Under Section 15.247 of The FCC Rules

3.2 Uncertainty of Test

Measurement	Value
Occupied Channel Bandwidth	±5 %
RF output power, conducted	±1.5 dB
Power Spectral Density, conducted	±3.0 dB
Unwanted Emissions, conducted	±3.0 dB
Supply voltages	±3 %
Time	±5 %
Radiated Emission (30MHz ~ 1000MHz)	±4.80 dB
Radiated Emission (1GHz ~ 18GHz)	±4.82 dB
The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.	

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Antenna requirement	47 CFR Part 15.247	Part 15.203	Pass
Conducted Emission at AC power line	47 CFR Part 15.247	47 CFR 15.207(a)	Pass
Occupied Bandwidth	47 CFR Part 15.247	47 CFR 15.215(c)	Pass
Maximum Conducted Output Power	47 CFR Part 15.247	47 CFR 15.247(b)(1)	Pass
Channel Separation	47 CFR Part 15.247	47 CFR 15.247(a)(1)	Pass
Number of Hopping Frequencies	47 CFR Part 15.247	47 CFR 15.247(a)(1)(iii)	Pass
Dwell Time	47 CFR Part 15.247	47 CFR 15.247(a)(1)(iii)	Pass
Emissions in non-restricted frequency bands	47 CFR Part 15.247	47 CFR 15.247(d)	Pass
Band edge emissions (Radiated)	47 CFR Part 15.247	47 CFR 15.247(d)	Pass
Emissions in restricted frequency bands (below 1GHz)	47 CFR Part 15.247	47 CFR 15.247(d)	Pass
Emissions in restricted frequency bands (above 1GHz)	47 CFR Part 15.247	47 CFR 15.247(d)	Pass

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4 Test Configuration

4.1 Test Equipment List

Radiated test method					
Test Equipment	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
EMI Receiver	Rohde &Schwarz	ESCI7	101032	2024/10/25	2025/10/24
Signal Analyzer	Rohde & Schwarz	FSQ40	100010	2024/10/25	2025/10/24
Log periodic antenna	Schwarzbeck	VULB 9168	01328	2024/10/28	2025/10/27
Preamplifier (30MHz ~ 1GHz)	Schwarzbeck	BBV9744	00246	2024/09/24	2025/09/23
Horn Antenna (1GHz ~18GHz)	Schwarzbeck	BBHA9120D	2597	2024/10/30	2025/10/29
Horn Antenna (15GHz ~ 40GHz)	SCHWARZBECK	BBHA9170	1157	2024/10/24	2025/10/23
Preamplifier (1GHz ~ 40GHz)	TST Pass	LNA10180G45	246	2024/09/24	2025/09/23
Test Software	Frad	EZ_EMC	Version: FA-03A2 RE+		

Conducted Emission Test					
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
EMI Receiver	Rohde & Schwarz	ESCI3	101422	2024/10/25	2025/10/24
V-LISN	Schwarzbeck	NSLK 8127	01073	2024/10/25	2025/10/24
Coaxial Switcher	Schwarzbeck	CX210	CX210	/	/
Pulse Limiter	Schwarzbeck	VTSD 9561-F	00953	/	/
Test Software	Frad	EZ_EMC	Version: EMC-CON 3A1.1+		

Conducted test method					
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Spectrum Analyzer	Keysight	N9020A	MY50410020	2024/10/25	2025/10/24
ESG Vector Signal Generator	Agilent	E4438C	MY45094854	2024/10/25	2025/10/24
MXG Vector Signal Generator	Agilent	N5182A	MY46240163	2024/10/25	2025/10/24
Wideband Radio Communication Tester	Rohde&Schwarz	CMW500	161997	2024/10/25	2025/10/24
Temperature Humidity Chamber	ZZCKONG	ZZ-K02A	20210928007	2024/10/25	2025/10/24
DC Power Supply	Tongmen	etm-6050c	20211026123	2024/10/25	2025/10/24
RF Control Unit	Techy	TR1029-1	/	2024/10/25	2025/10/24
RF Sensor Unit	Techy	TR1029-2	/	2024/10/25	2025/10/24
Test Software	TST Pass	/	Version: 2.0		

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4.2 Test Auxiliary Equipment

The EUT was tested as an independent device.

4.3 Test Modes

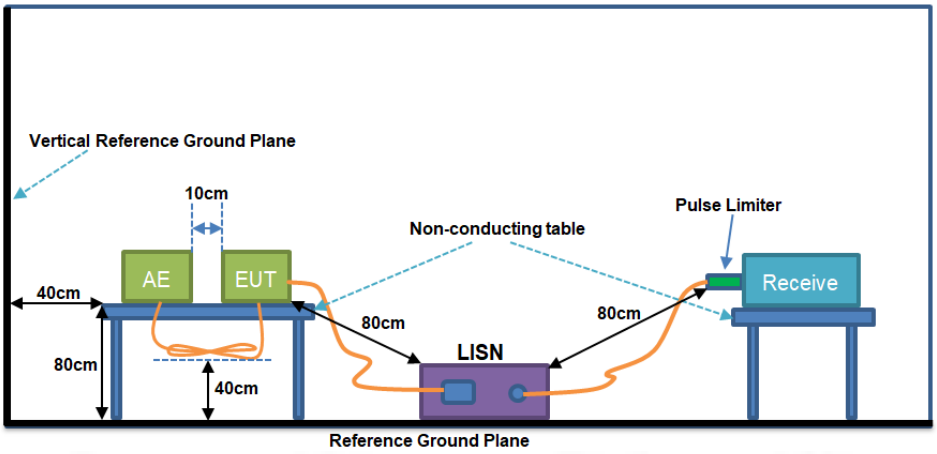
No.	Test Modes	Description
TM1	TX-GFSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with GFSK modulation.
TM2	TX-Pi/4DQPSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with Pi/4DQPSK modulation.
TM3	TX-8DPSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with 8DPSK modulation.
TM4	TX-GFSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with GFSK modulation,.
TM5	TX-Pi/4DQPSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with Pi/4DQPSK modulation.
TM6	TX-8DPSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with 8DPSK modulation.

4.4 Test software

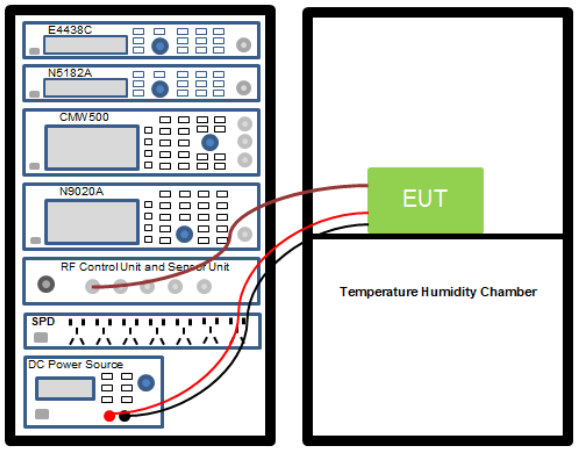
Test software:	FCC assist	Version:	1.0.0.2
Power Class:	4		

4.5 Test Setup Block

1) Conducted emission measurement:

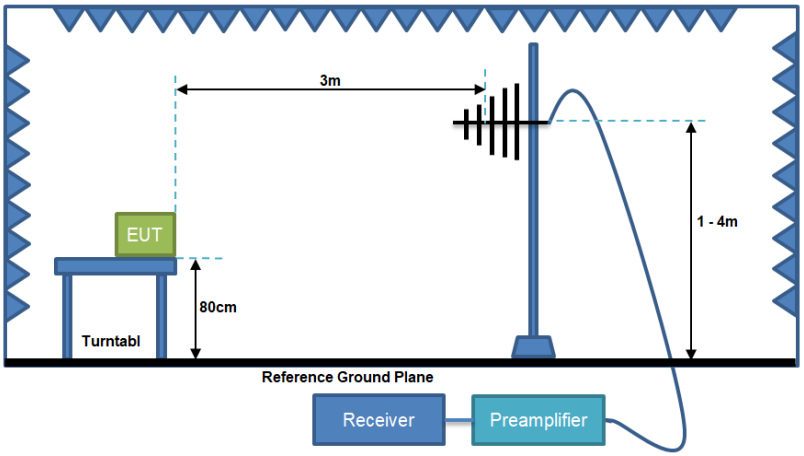


2) Conducted test method:

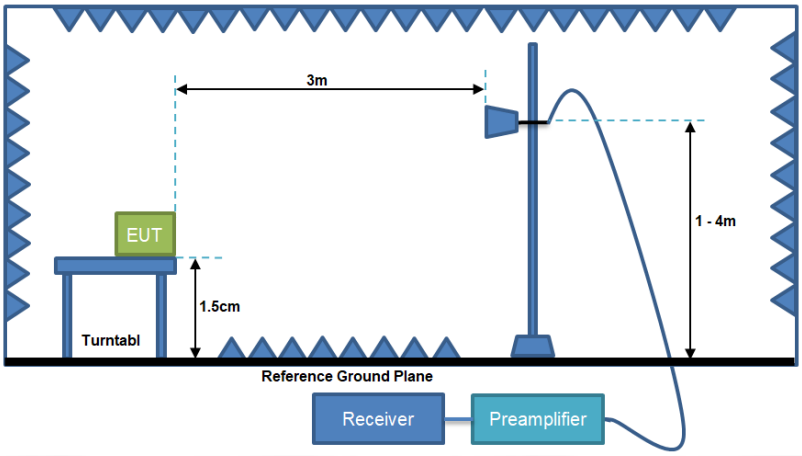


3) Radiated test method:

Below 1GHz



Above 1GHz



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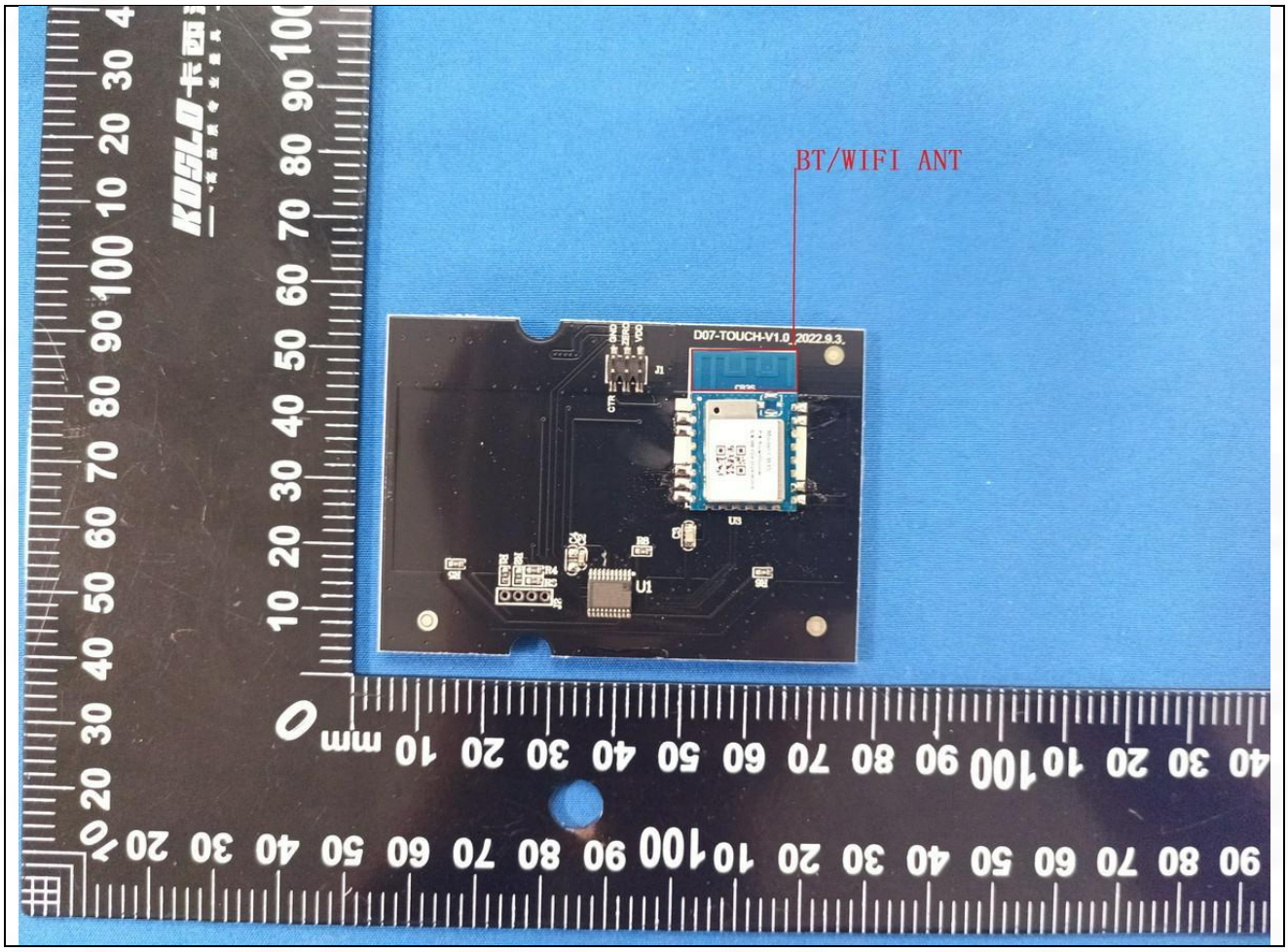
5 Evaluation Results (Evaluation)

5.1 Antenna requirement

Test Requirement:	An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.

5.1.1 Conclusion:



6 Radio Spectrum Matter Test Results (RF)

6.1 Conducted Emission at AC power line

Test Requirement:	Except as shown in paragraphs (b)and (c)of this section, for an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies, within the band 150 kHz to 30 MHz, shall not exceed the limits in the following table, as measured using a 50 μH/50 ohms line impedance stabilization network (LISN).
Test Method:	Refer to ANSI C63.10-2020 section 6.2, standard test method for ac power-line conducted emissions from unlicensed wireless devices
Test Limit:	

Frequency of emission (MHz)	Conducted limit (dBμV)	
	Quasi-peak	Average
0.15-0.5	66 to 56*	56 to 46*
0.5-5	56	46
5-30	60	50

*Decreases with the logarithm of the frequency.

6.1.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	47.8 %
Atmospheric Pressure:	1010 hpa
Test Voltage	AC 120V 60Hz

6.1.2 Test Data:

TM1 / Line: Line / Band: 2.4G

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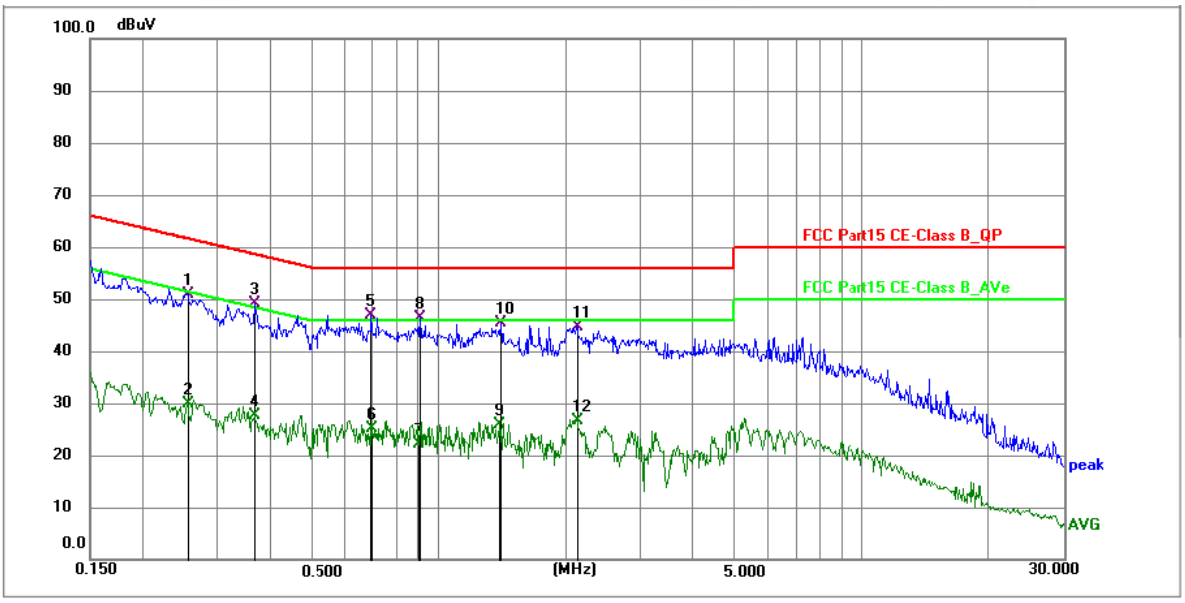

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.2535	40.35	10.63	50.98	61.64	-10.66	QP	P	
2	0.2535	19.13	10.63	29.76	51.64	-21.88	AVG	P	
3	0.3653	38.42	10.62	49.04	58.61	-9.57	QP	P	
4	0.3653	17.12	10.62	27.74	48.61	-20.87	AVG	P	
5 *	0.6945	36.24	10.73	46.97	56.00	-9.03	QP	P	
6	0.6990	14.43	10.73	25.16	46.00	-20.84	AVG	P	
7	0.9012	11.34	10.76	22.10	46.00	-23.90	AVG	P	
8	0.9060	35.65	10.76	46.41	56.00	-9.59	QP	P	
9	1.4010	15.13	10.74	25.87	46.00	-20.13	AVG	P	
10	1.4100	34.71	10.74	45.45	56.00	-10.55	QP	P	
11	2.1300	34.51	10.04	44.55	56.00	-11.45	QP	P	
12	2.1300	16.48	10.04	26.52	46.00	-19.48	AVG	P	

Note:Margin=Level-Limit=Reading+factor-Limit

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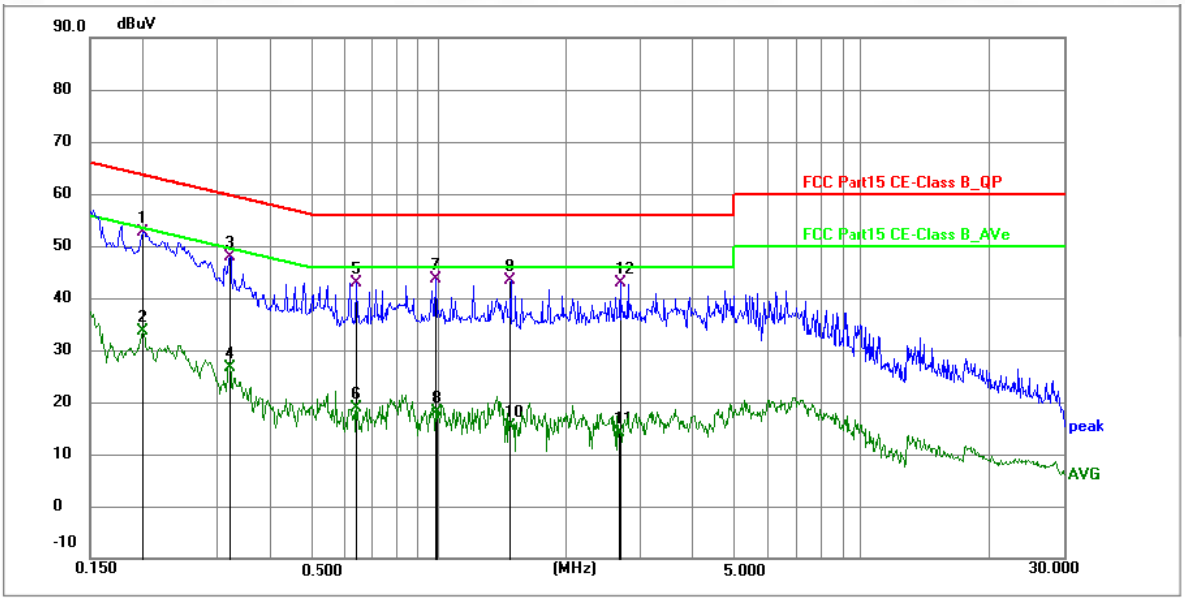
TM1 / Line: Neutral / Band: 2.4G / BW: 1 / CH: M



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1 *	0.1995	41.96	10.63	52.59	63.63	-11.04	QP	P	
2	0.1995	22.99	10.63	33.62	53.63	-20.01	AVG	P	
3	0.3200	37.23	10.62	47.85	59.71	-11.86	QP	P	
4	0.3200	15.92	10.62	26.54	49.71	-23.17	AVG	P	
5	0.6401	32.11	10.69	42.80	56.00	-13.20	QP	P	
6	0.6401	8.28	10.69	18.97	46.00	-27.03	AVG	P	
7	0.9870	32.82	10.78	43.60	56.00	-12.40	QP	P	
8	0.9915	7.47	10.78	18.25	46.00	-27.75	AVG	P	
9	1.4819	32.71	10.74	43.45	56.00	-12.55	QP	P	
10	1.4819	4.71	10.74	15.45	46.00	-30.55	AVG	P	
11	2.6700	6.71	7.35	14.06	46.00	-31.94	AVG	P	
12	2.6880	35.51	7.26	42.77	56.00	-13.23	QP	P	

Note:Margin=Level-Limit=Reading+factor-Limit

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6.2 Occupied Bandwidth

Test Requirement:	Intentional radiators operating under the alternative provisions to the general emission limits, as contained in §§ 15.217 through 15.257 and in subpart E of this part, must be designed to ensure that the 20 dB bandwidth of the emission, or whatever bandwidth may otherwise be specified in the specific rule section under which the equipment operates, is contained within the frequency band designated in the rule section under which the equipment is operated.
Test Method:	Occupied bandwidth—relative measurement procedure
Test Limit:	Intentional radiators operating under the alternative provisions to the general emission limits, as contained in §§ 15.217 through 15.257 and in subpart E of this part, must be designed to ensure that the 20 dB bandwidth of the emission, or whatever bandwidth may otherwise be specified in the specific rule section under which the equipment operates, is contained within the frequency band designated in the rule section under which the equipment is operated.
Procedure:	a) The spectrum analyzer center frequency is set to the nominal EUT channel center frequency. The span range for the EMI receiver or spectrum analyzer shall be between two times and five times the OBW. b) The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW and video bandwidth (VBW) shall be approximately three times RBW, unless otherwise specified by the applicable requirement. c) Set the reference level of the instrument as required, keeping the signal from exceeding the maximum input mixer level for linear operation. In general, the peak of the spectral envelope shall be more than [10 log (OBW/RBW)] below the reference level. Specific guidance is given in 4.1.5.2. d) Steps a) through c) might require iteration to adjust within the specified tolerances. e) The dynamic range of the instrument at the selected RBW shall be more than 10 dB below the target “−xx dB down” requirement; that is, if the requirement calls for measuring the −20 dB OBW, the instrument noise floor at the selected RBW shall be at least 30 dB below the reference value. f) Set detection mode to peak and trace mode to max hold. g) Determine the reference value: Set the EUT to transmit an unmodulated carrier or modulated signal, as applicable. Allow the trace to stabilize. Set the spectrum analyzer marker to the highest level of the displayed trace (this is the reference value). h) Determine the “−xx dB down amplitude” using [(reference value) − xx]. Alternatively, this calculation may be made by using the marker-delta function of the instrument. i) If the reference value is determined by an unmodulated carrier, then turn the EUT modulation ON, and either clear the existing trace or start a new trace on the spectrum analyzer and allow the new trace to stabilize. Otherwise, the trace from step g) shall be used for step j). j) Place two markers, one at the lowest frequency and the other at the highest frequency of the envelope of the spectral display, such that each marker is at or slightly below the “-xx dB down amplitude” determined in step h). If a marker is below this “−xx dB down amplitude” value, then it shall be as close as possible to this value. The occupied bandwidth is the frequency difference between the two markers. Alternatively, set a marker at the lowest frequency of the envelope of the spectral display, such that the marker is at or slightly below the “-xx dB down amplitude” determined in step h). Reset the marker-delta function and move the marker to the other side of the emission until the delta marker amplitude is at the same level as the reference marker amplitude. The marker-delta frequency reading at this point is the specified emission bandwidth.

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	k) The occupied bandwidth shall be reported by providing plot(s) of the measuring instrument display; the plot axes and the scale units per division shall be clearly labeled. Tabular data may be reported in addition to the plot(s).

6.2.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	45.2 %
Atmospheric Pressure:	1010 hpa
Test Voltage	DC 5V

6.2.2 Test Data:

Please Refer to Appendix for Details.

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6.3 Maximum Conducted Output Power

Test Requirement:	For frequency hopping systems operating in the 2400-2483.5 MHz band employing at least 75 non-overlapping hopping channels, and all frequency hopping systems in the 5725-5850 MHz band: 1 watt. For all other frequency hopping systems in the 2400-2483.5 MHz band: 0.125 watts.
Test Method:	Output power test procedure for frequency-hopping spread-spectrum (FHSS) devices
Test Limit:	For frequency hopping systems operating in the 2400-2483.5 MHz band employing at least 75 non-overlapping hopping channels, and all frequency hopping systems in the 5725-5850 MHz band: 1 watt. For all other frequency hopping systems in the 2400-2483.5 MHz band: 0.125 watts.
Procedure:	This is an RF-conducted test to evaluate maximum peak output power. Use a direct connection between the antenna port of the unlicensed wireless device and the spectrum analyzer, through suitable attenuation. The hopping shall be disabled for this test: a) Use the following spectrum analyzer settings: 1) Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel. 2) RBW > 20 dB bandwidth of the emission being measured. 3) VBW >= RBW. 4) Sweep: Auto. 5) Detector function: Peak. 6) Trace: Max hold. b) Allow trace to stabilize. c) Use the marker-to-peak function to set the marker to the peak of the emission. d) The indicated level is the peak output power, after any corrections for external attenuators and cables. e) A plot of the test results and setup description shall be included in the test report. NOTE—A peak responding power meter may be used, where the power meter and sensor system video bandwidth is greater than the occupied bandwidth of the unlicensed wireless device, rather than a spectrum analyzer.

6.3.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	45.2 %
Atmospheric Pressure:	1010 hpa
Test Voltage	DC 5V

6.3.2 Test Data:

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6.4 Channel Separation

Test Requirement:	Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater. Alternatively, frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW.
Test Method:	Carrier frequency separation
Test Limit:	Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater. Alternatively, frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Wide enough to capture the peaks of two adjacent channels. b) RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel. c) Video (or average) bandwidth (VBW) ≥ RBW. d) Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels. Compliance of an EUT with the appropriate regulatory limit shall be determined. A plot of the data shall be included in the test report.

6.4.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	45.2 %
Atmospheric Pressure:	1010 hpa
Test Voltage	DC 5V

6.4.2 Test Data:

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6.5 Number of Hopping Frequencies

Test Requirement:	Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Test Method:	Number of hopping frequencies
Test Limit:	Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: The frequency band of operation. Depending on the number of channels the device supports, it may be necessary to divide the frequency range of operation across multiple spans, to allow the individual channels to be clearly seen. b) RBW: To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller. c) VBW ≥ RBW. d) Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. It might prove necessary to break the span up into subranges to show clearly all of the hopping frequencies. Compliance of an EUT with the appropriate regulatory limit shall be determined for the number of hopping channels. A plot of the data shall be included in the test report.

6.5.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	45.2 %
Atmospheric Pressure:	1010 hpa
Test Voltage	DC 5V

6.5.2 Test Data:

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6.6 Dwell Time

Test Requirement:	Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Test Method:	Time of occupancy (dwell time)
Test Limit:	Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Zero span, centered on a hopping channel. b) RBW shall be <= channel spacing and where possible RBW should be set >> 1 / T, where T is the expected dwell time per channel. c) Sweep: As necessary to capture the entire dwell time per hopping channel; where possible use a video trigger and trigger delay so that the transmitted signal starts a little to the right of the start of the plot. The trigger level might need slight adjustment to prevent triggering when the system hops on an adjacent channel; a second plot might be needed with a longer sweep time to show two successive hops on a channel. d) Detector function: Peak. e) Trace: Max hold. Use the marker-delta function to determine the transmit time per hop. If this value varies with different modes of operation (data rate, modulation format, number of hopping channels, etc.), then repeat this test for each variation in transmit time. Repeat the measurement using a longer sweep time to determine the number of hops over the period specified in the requirements. The sweep time shall be equal to, or less than, the period specified in the requirements. Determine the number of hops over the sweep time and calculate the total number of hops in the period specified in the requirements, using the following equation: (Number of hops in the period specified in the requirements) = (number of hops on spectrum analyzer) × (period specified in the requirements / analyzer sweep time) The average time of occupancy is calculated from the transmit time per hop multiplied by the number of hops in the period specified in the requirements. If the number of hops in a specific time varies with different modes of operation (data rate, modulation format, number of hopping channels, etc.), then repeat this test for each variation. The measured transmit time and time between hops shall be consistent with the values described in the operational description for the EUT.

6.6.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	45.2 %
Atmospheric Pressure:	1010 hpa
Test Voltage	DC 5V

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6.6.2 Test Data:

Please Refer to Appendix for Details.

6.7 Emissions in non-restricted frequency bands

Test Requirement:	In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in § 15.209(a) is not required.
Test Method:	Conducted spurious emissions test methodology
Test Limit:	In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in § 15.209(a) is not required.
Procedure:	Conducted spurious emissions shall be measured for the transmit frequency, per 5.5 and 5.6, and at the maximum transmit powers. Connect the primary antenna port through an attenuator to the spectrum analyzer input; in the results, account for all losses between the unlicensed wireless device output and the spectrum analyzer. The instrument shall span 30 MHz to 10 times the operating frequency in GHz, with a resolution bandwidth of 100 kHz, video bandwidth of 300 kHz, and a coupled sweep time with a peak detector. The band 30 MHz to the highest frequency may be split into smaller spans, as long as the entire spectrum is covered.

6.7.1 E.U.T. Operation:

Operating Environment:	
Temperature:	22.3 °C
Humidity:	45.2 %
Atmospheric Pressure:	1010 hpa
Test Voltage	DC 5V

6.7.2 Test Data:

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6.8 Band edge emissions (Radiated)

<table>
<tr><td>Test Requirement:</td><td colspan="3">In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`</td></tr>
<tr><td>Test Method:</td><td colspan="3">Radiated emissions tests</td></tr>
<tr><td rowspan="9">Test Limit:</td><td>Frequency (MHz)</td><td>Field strength (microvolts/meter)</td><td>Measurement distance (meters)</td></tr>
<tr><td>0.009-0.490</td><td>2400/F(kHz)</td><td>300</td></tr>
<tr><td>0.490-1.705</td><td>24000/F(kHz)</td><td>30</td></tr>
<tr><td>1.705-30.0</td><td>30</td><td>30</td></tr>
<tr><td>30-88</td><td>100 **</td><td>3</td></tr>
<tr><td>88-216</td><td>150 **</td><td>3</td></tr>
<tr><td>216-960</td><td>200 **</td><td>3</td></tr>
<tr><td>Above 960</td><td>500</td><td>3</td></tr>
<tr><td colspan="3">** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.</td></tr>
<tr><td>Procedure:</td><td colspan="3">ANSI C63.10-2020 section 6.10.5.2</td></tr>
</table>

6.8.1 E.U.T. Operation:

Operating Environment:	
Temperature:	25 °C
Humidity:	49.5 %
Atmospheric Pressure:	1010 hpa
Test Voltage	AC 120V 60Hz

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6.8.2 Test Data:

Remark: During the test, pre-scan GFSK, π/4 DQPSK, 8DPSK mode, found GFSK was worse case mode. The report only reflects the test data of worst mode.

Test Mode: GFSK Test Channel: Lowest channel, Test Polarization: Vertical							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
2310.00	51.38	3.85	55.23	74.00	-18.77	Peak	Pass
2310.00	41.57	3.85	45.42	54.00	-8.58	AVG	Pass
2390.00	52.66	3.91	56.57	74.00	-17.43	Peak	Pass
2390.00	41.72	3.91	45.63	54.00	-8.37	AVG	Pass
Test Channel: Lowest channel, Test Polarization: Horizontal							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
2310.00	52.43	3.85	56.28	74.00	-17.72	Peak	Pass
2310.00	42.33	3.85	46.18	54.00	-7.82	AVG	Pass
2390.00	52.49	3.91	56.41	74.00	-17.59	Peak	Pass
2390.00	42.05	3.91	45.97	54.00	-8.03	AVG	Pass
Test Channel: Highest channel, Test Polarization: Vertical							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
2483.50	50.68	3.99	54.67	74.00	-19.33	Peak	Pass
2483.50	40.82	3.99	44.80	54.00	-9.20	AVG	Pass
2500.00	51.90	4.00	55.90	74.00	-18.10	Peak	Pass
2500.00	41.07	4.00	45.07	54.00	-8.93	AVG	Pass
Test Channel: Highest channel, Test Polarization: Horizontal							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
2483.50	50.78	3.99	54.77	74.00	-19.23	Peak	Pass
2483.50	39.82	3.99	43.81	54.00	-10.19	AVG	Pass
2500.00	52.47	4.00	56.47	74.00	-17.53	Peak	Pass
2500.00	42.32	4.00	46.32	54.00	-7.68	AVG	Pass

Note:Margin=Level-Limit=Reading+factor-Limit

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6.9 Emissions in restricted frequency bands (below 1GHz)

Test Requirement:	In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	Radiated emissions tests
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.

Procedure:	ANSI C63.10-2020 section 6.6.4

6.9.1 E.U.T. Operation:

Operating Environment:	
Temperature:	25 °C
Humidity:	49.5 %
Atmospheric Pressure:	1010 hpa
Test Voltage	AC 120V 60Hz

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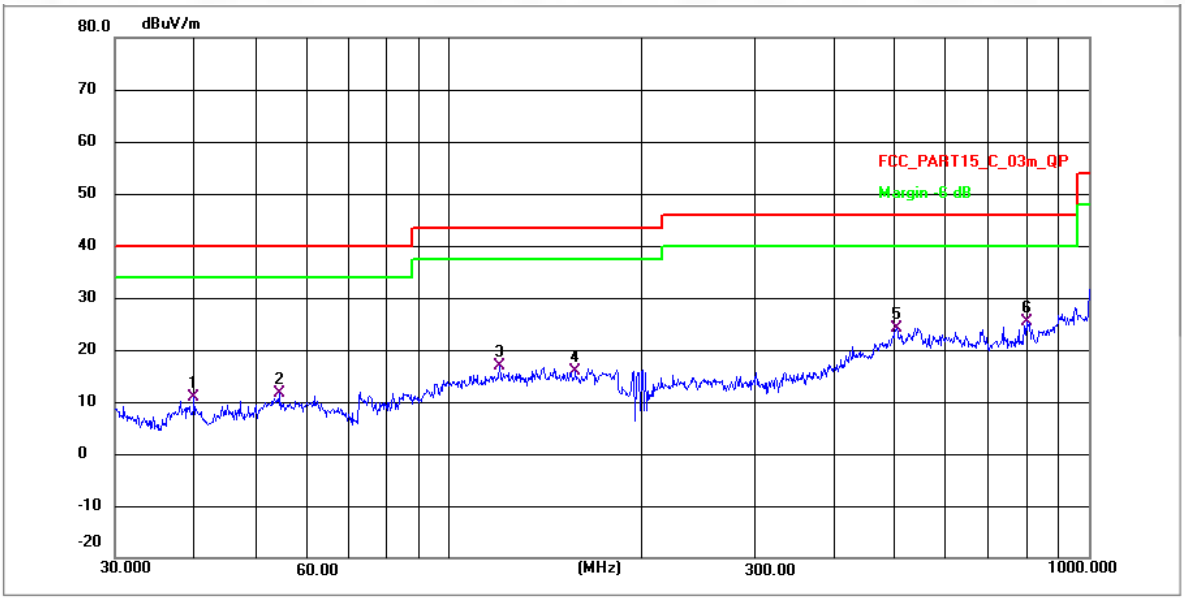
6.9.2 Test Data:

TM1 / Polarization: Horizontal



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	39.9941	29.39	-18.40	10.99	40.00	-29.01	QP	P
2	54.4515	29.79	-18.24	11.55	40.00	-28.45	QP	P
3	120.0660	45.04	-28.05	16.99	43.50	-26.51	QP	P
4	157.5587	43.71	-27.71	16.00	43.50	-27.50	QP	P
5	502.9395	45.21	-21.17	24.04	46.00	-21.96	QP	P
6 *	798.9796	49.19	-23.72	25.47	46.00	-20.53	QP	P

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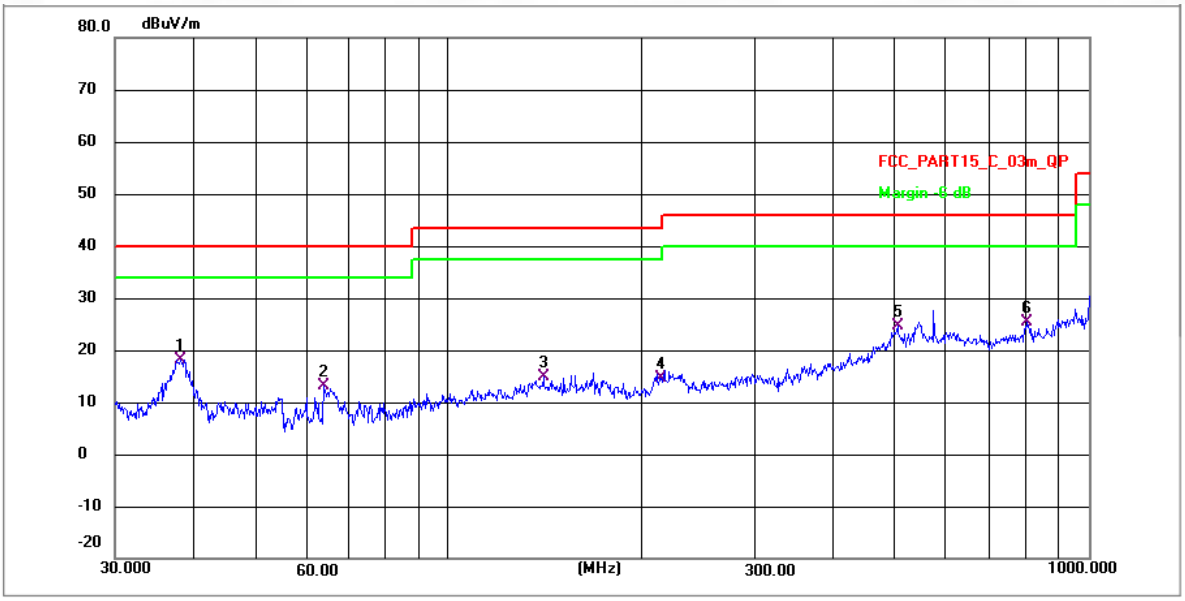
TM1 / Polarization: Vertical



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	38.0782	38.65	-20.57	18.08	40.00	-21.92	QP	P
2	63.6471	33.32	-20.10	13.22	40.00	-26.78	QP	P
3	140.8350	42.72	-27.86	14.86	43.50	-28.64	QP	P
4	214.8907	41.31	-26.68	14.63	43.50	-28.87	QP	P
5	503.8220	45.87	-21.18	24.69	46.00	-21.31	QP	P
6 *	800.3817	49.05	-23.72	25.33	46.00	-20.67	QP	P

Note:Margin=Level-Limit=Reading+factor-Limit

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6.10 Emissions in restricted frequency bands (above 1GHz)

Test Requirement:	In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	Radiated emissions tests
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.

Procedure:	ANSI C63.10-2020 section 6.6.4

6.10.1 E.U.T. Operation:

Operating Environment:	
Temperature:	25 °C
Humidity:	49.5 %
Atmospheric Pressure:	1010 hpa
Test Voltage	AC 120V 60Hz

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6.10.2 Test Data:

Remark: During the test, pre-scan GFSK, π/4 DQPSK, 8DPSK mode, found GFSK was worse case mode. The report only reflects the test data of worst mode.

Test Mode: GFSK Test Channel: Lowest channel, Test Polarization: Vertical							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
4804.000	91.49	-48.83	42.66	74.00	-31.34	peak	P
4804.000	90.06	-48.83	41.23	54.00	-12.77	AV	P
7206.000	90.06	-46.88	43.18	74.00	-30.82	peak	P
7206.000	90.06	-46.88	43.18	54.00	-10.82	AV	P
Test Channel: Lowest channel, Test Polarization: Horizontal							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
4804.000	92.41	-48.83	43.58	74.00	-30.42	peak	P
4804.000	90.88	-48.83	42.05	54.00	-11.95	AV	P
7206.000	90.88	-46.88	44.00	74.00	-30.00	peak	P
7206.000	90.04	-46.88	43.16	54.00	-10.84	AV	P
Test Channel: Middle channel, Test Polarization: Vertical							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
4882.000	92.05	-48.82	43.23	54.00	-10.77	peak	P
4882.000	92.05	-48.82	43.23	74.00	-30.77	AV	P
7323.000	90.62	-46.87	43.75	54.00	-10.25	peak	P
7323.000	90.62	-46.87	43.75	74.00	-30.25	AV	P
Test Channel: Middle channel, Test Polarization: Horizontal							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
4882.000	92.79	-48.83	43.96	74.00	-30.04	peak	P
9764.000	92.79	-48.83	43.96	54.00	-10.04	AV	P
7323.000	91.26	-46.88	44.38	74.00	-29.62	peak	P
14646.000	91.26	-46.88	44.38	54.00	-9.62	AV	P

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Test Channel: Highest channel, Test Polarization: Vertical							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
4960.000	92.63	-48.71	43.92	74.00	-30.08	peak	P
4960.000	91.20	-48.71	42.49	54.00	-11.51	AV	P
7440.000	91.20	-46.76	44.44	74.00	-29.56	peak	P
7440.000	91.20	-46.76	44.44	54.00	-9.56	AV	P
Test Channel: Highest channel, Test Polarization: Horizontal							
Frequency (MHz)	Reading (dBμV)	Factor (dB)	Level (dBμV/m)	Limit (dBμV/m)	Marging (dB)	Detector	Result
4960.000	93.33	-48.71	44.62	74.00	-29.38	peak	P
4960.000	91.80	-48.71	43.09	54.00	-10.91	AV	P
7440.000	91.80	-46.76	45.04	74.00	-28.96	peak	P
7440.000	91.55	-46.76	44.79	54.00	-9.21	AV	P

Note:Margin=Level-Limit=Reading+factor-Limit

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Appendix

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BTF Testing Lab (Shenzhen) Co., Ltd.
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1. Bandwidth

1.1 OBW

1.1.1 Test Result

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	99% Occupied Bandwidth (MHz) Result	Verdict
GFSK	SISO	2402	DH5	1	0.750	Pass
		2441	DH5	1	0.751	Pass
		2480	DH5	1	0.749	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	1.147	Pass
		2441	2DH5	1	1.146	Pass
		2480	2DH5	1	1.145	Pass
8DPSK	SISO	2402	3DH5	1	1.157	Pass
		2441	3DH5	1	1.153	Pass
		2480	3DH5	1	1.151	Pass

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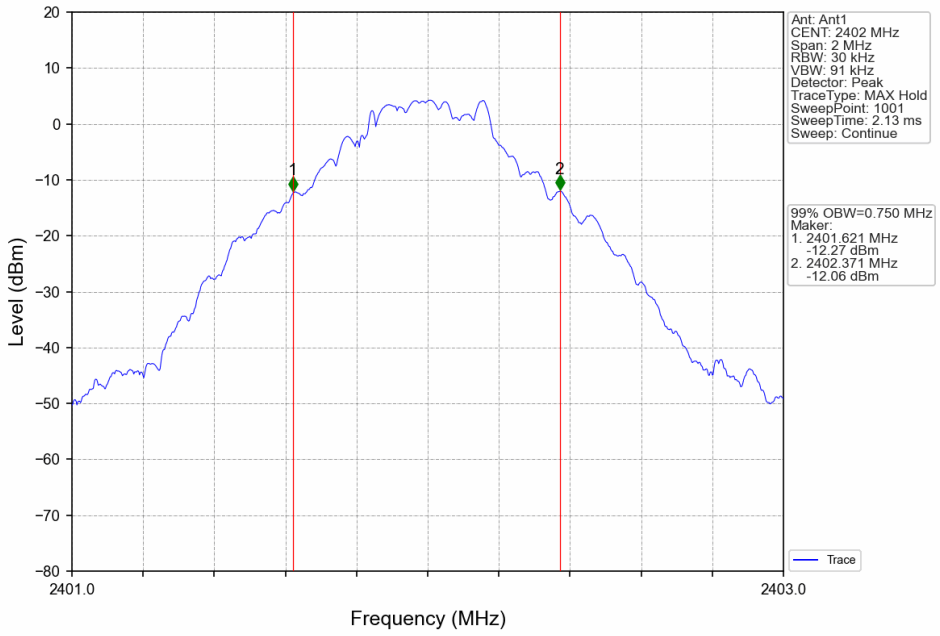
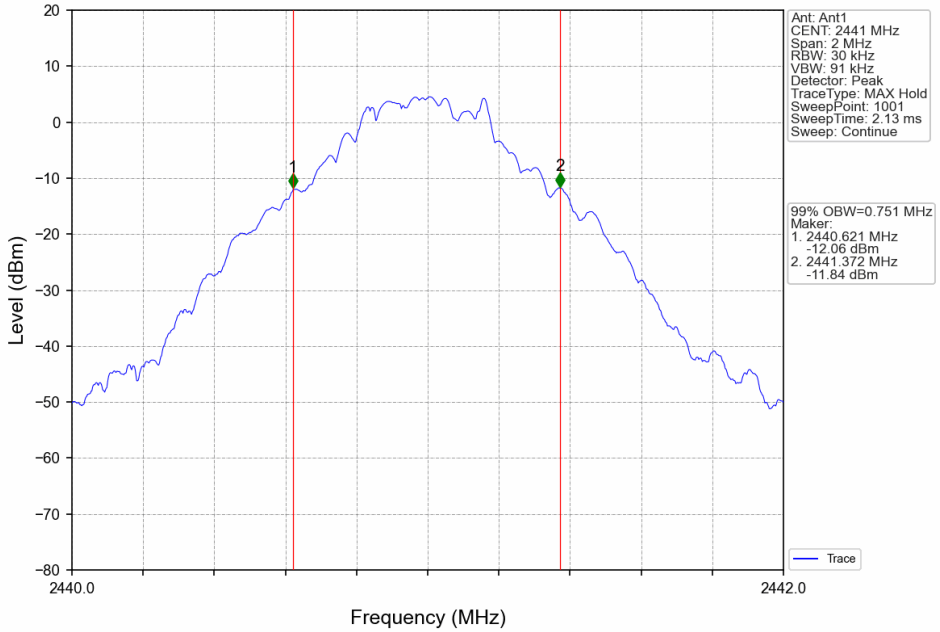
1.1.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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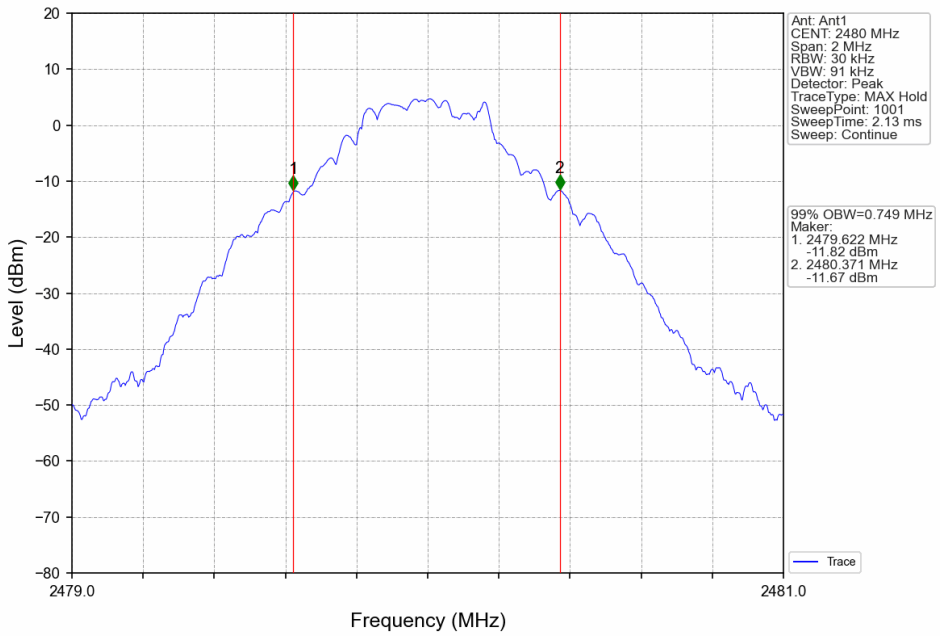
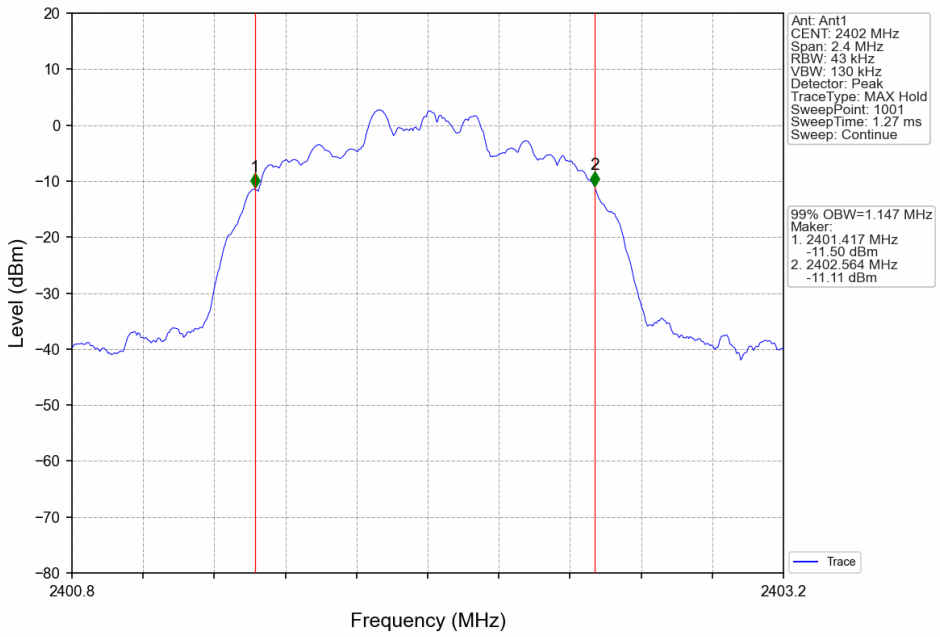
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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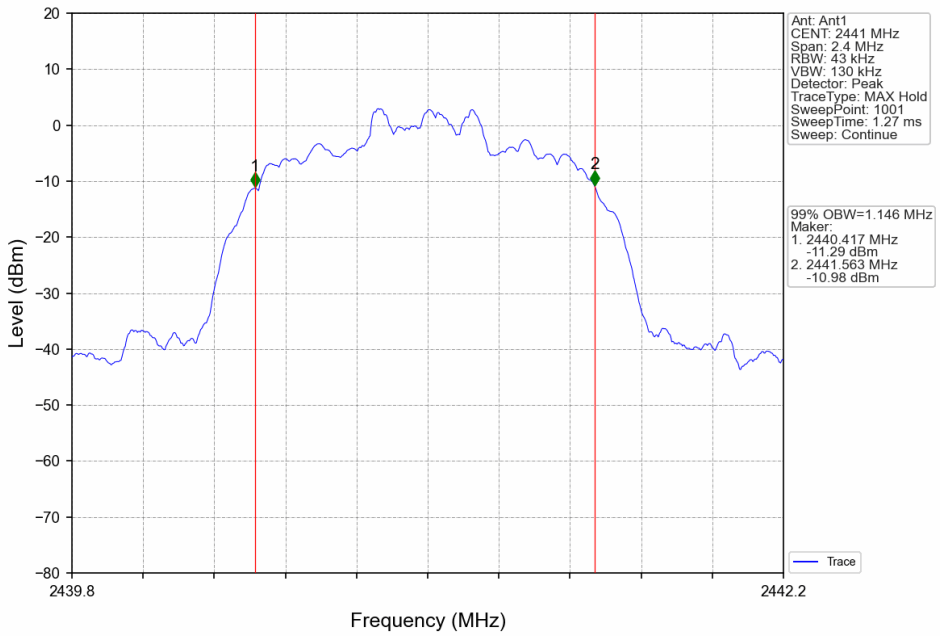
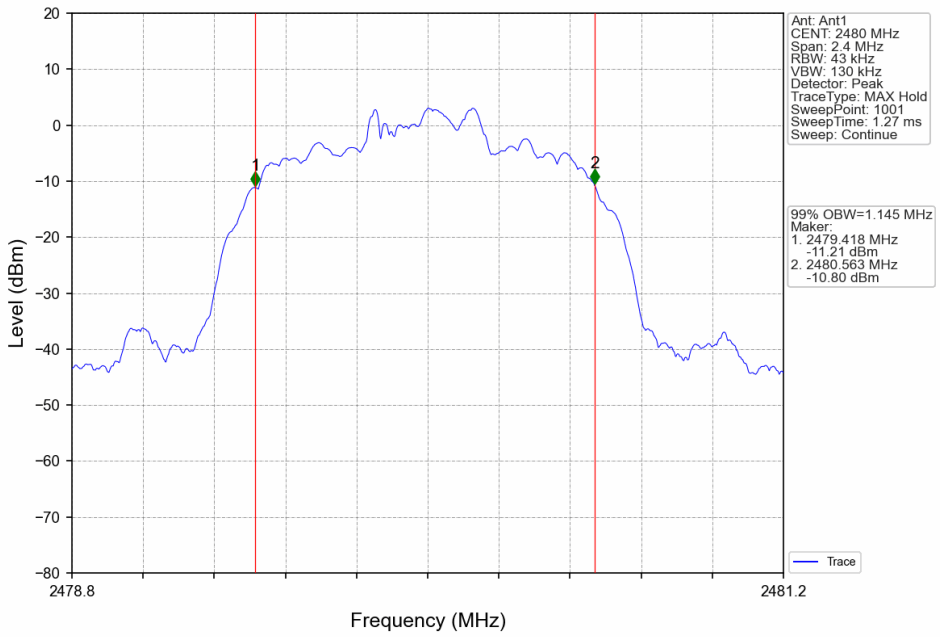
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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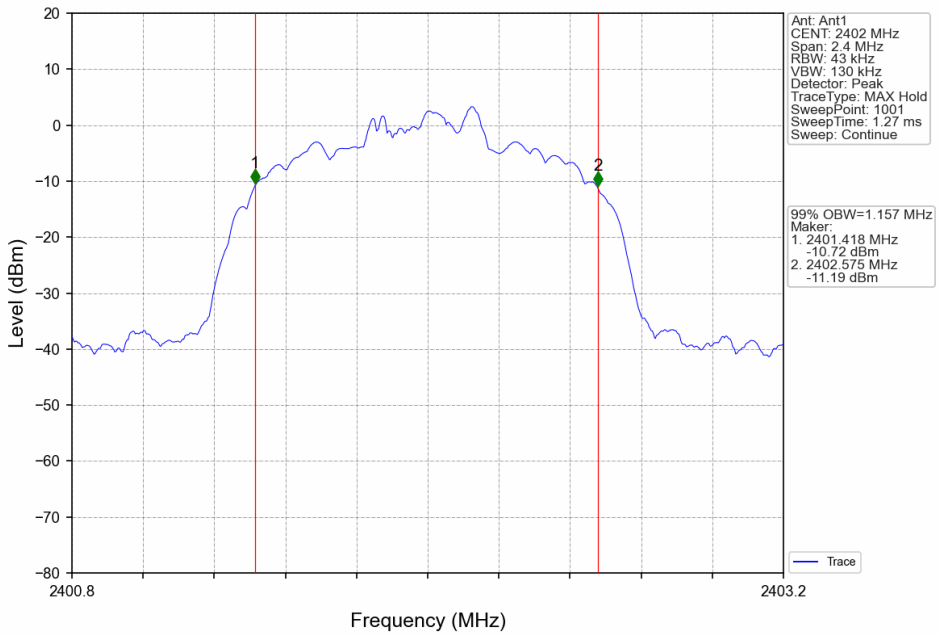
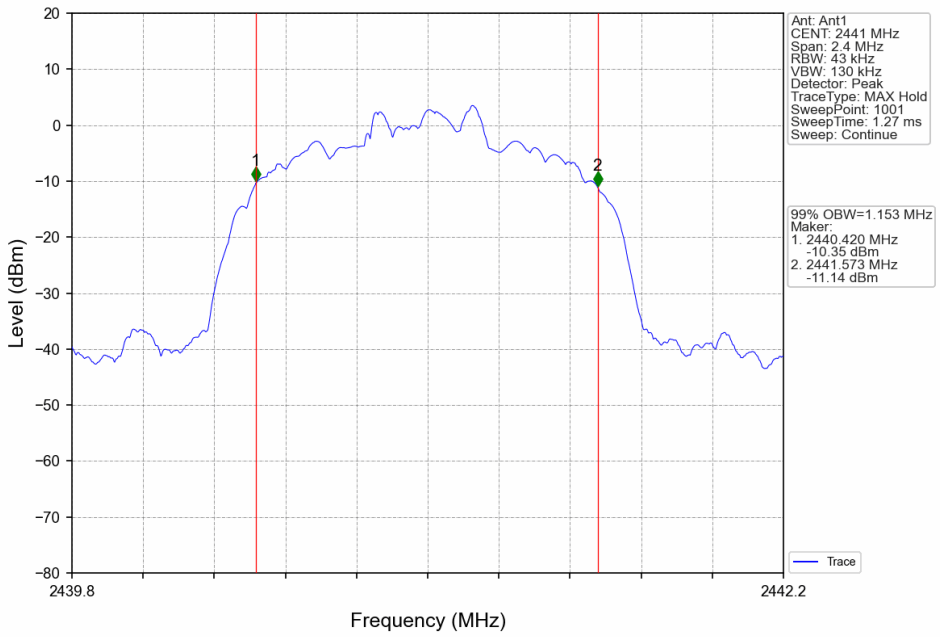
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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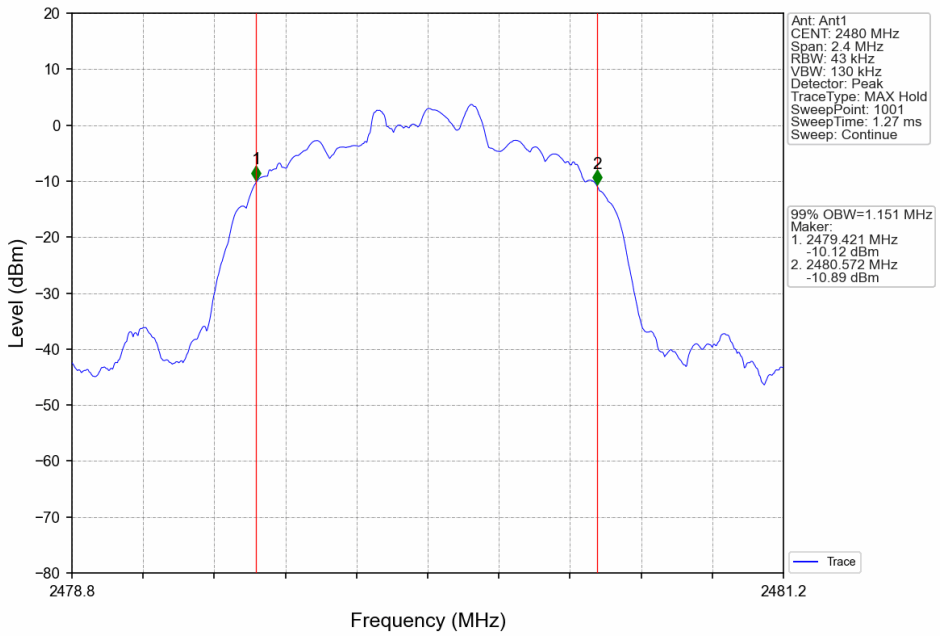
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



1.2 20dB BW

1.2.1 Test Result

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	20dB Bandwidth (MHz) Result	Verdict
GFSK	SISO	2402	DH5	1	0.852	Pass
		2441	DH5	1	0.848	Pass
		2480	DH5	1	0.850	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	1.285	Pass
		2441	2DH5	1	1.286	Pass
		2480	2DH5	1	1.281	Pass
8DPSK	SISO	2402	3DH5	1	1.297	Pass
		2441	3DH5	1	1.295	Pass
		2480	3DH5	1	1.293	Pass

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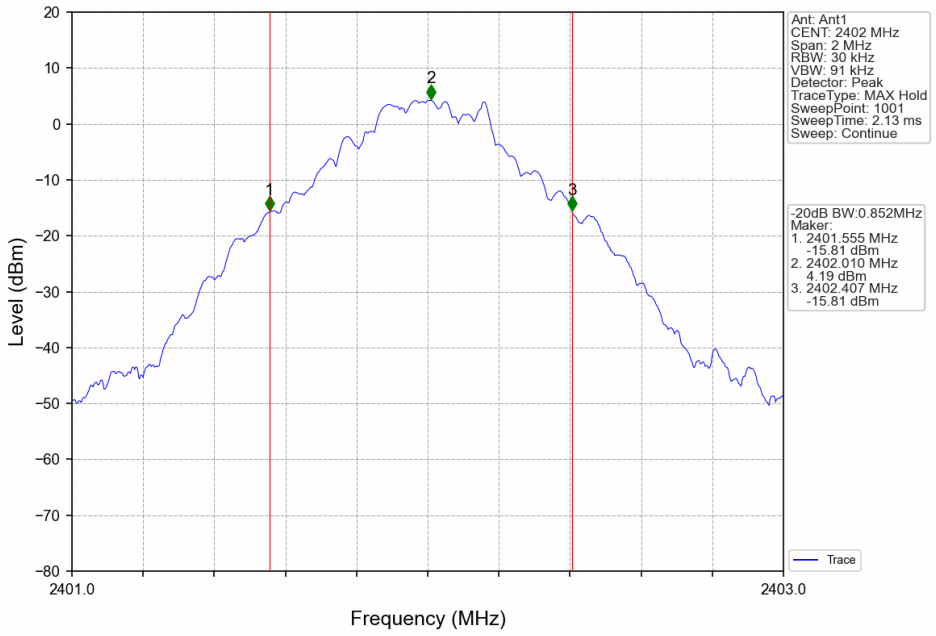
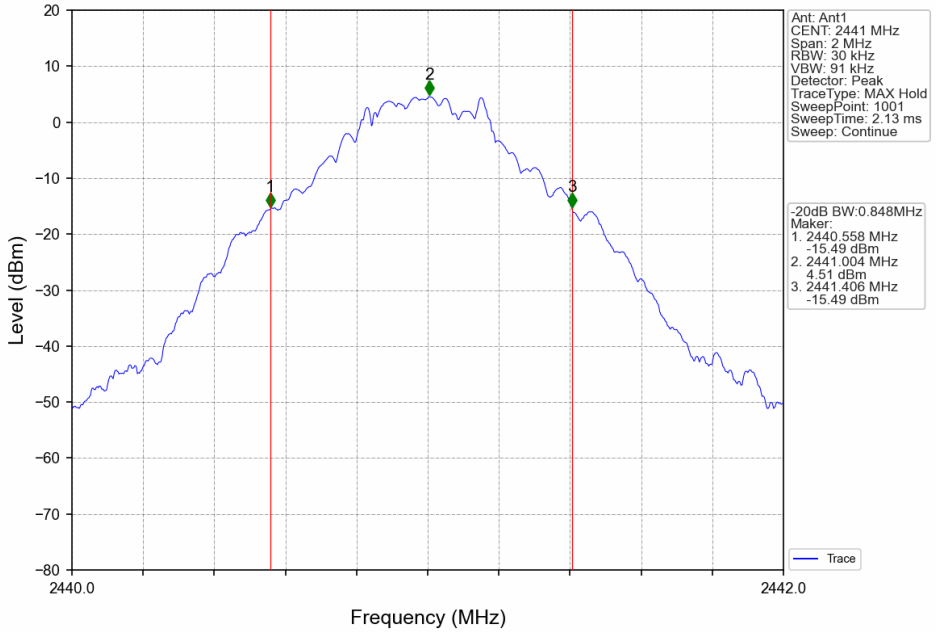
1.2.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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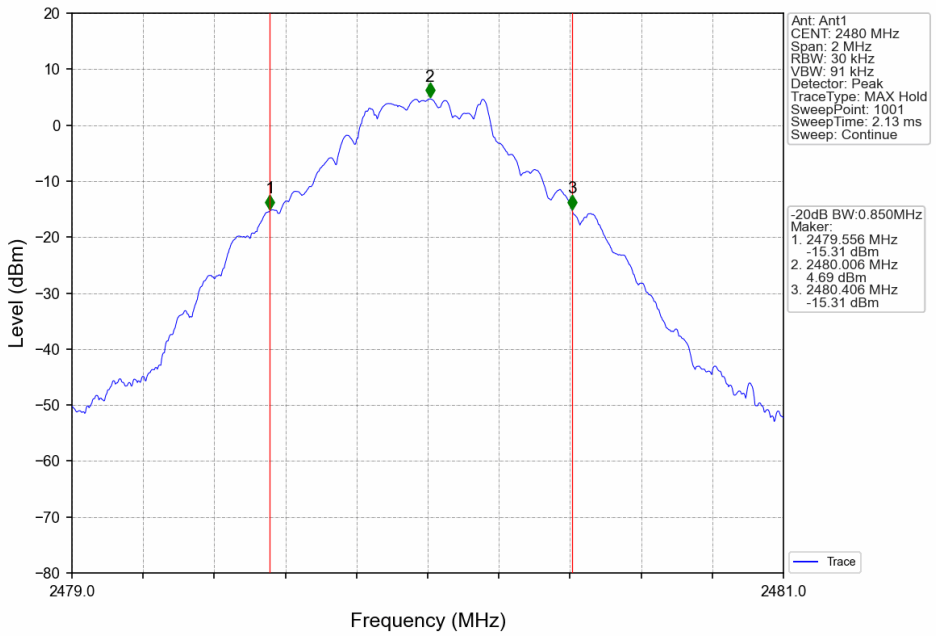
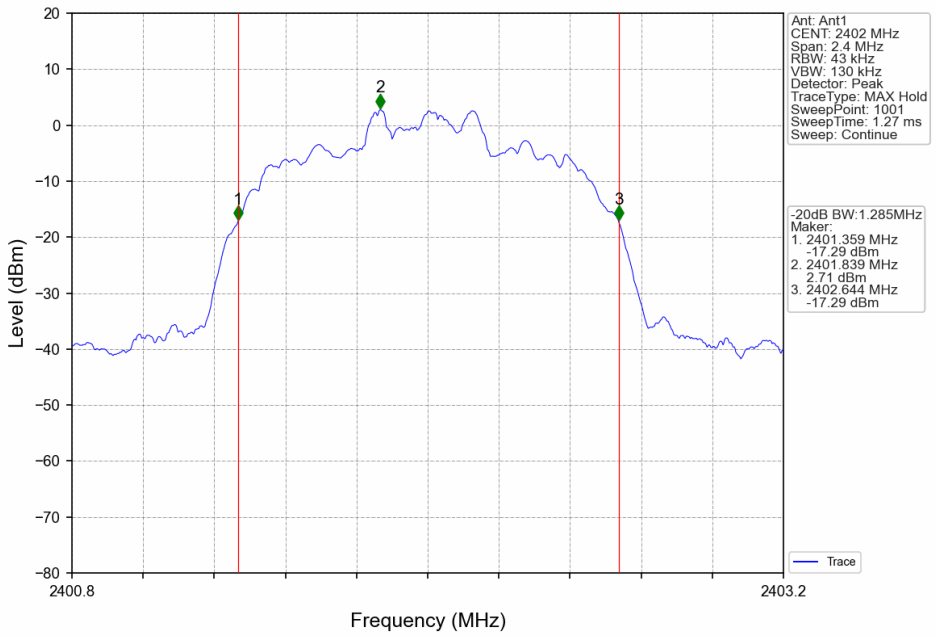
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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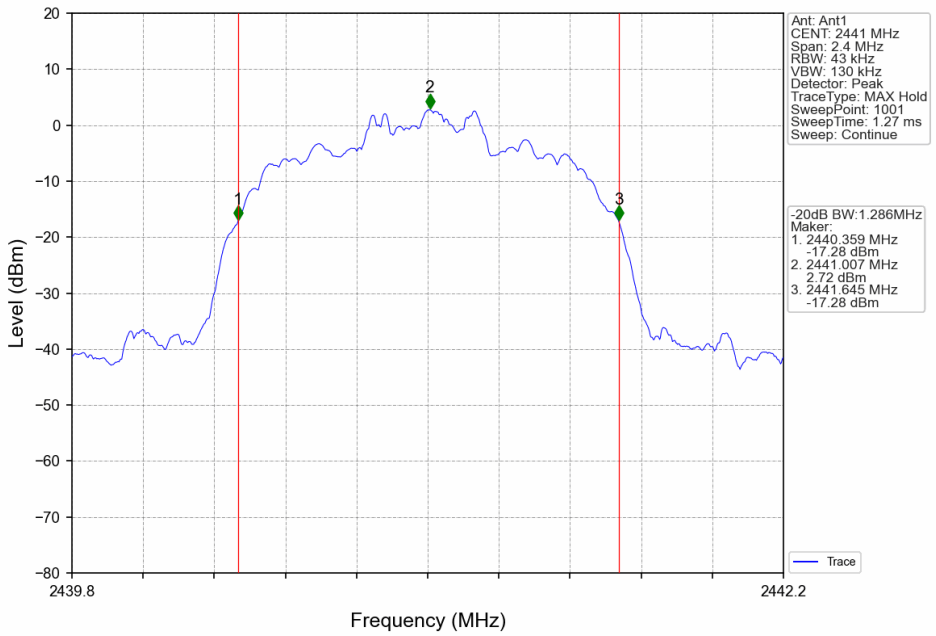
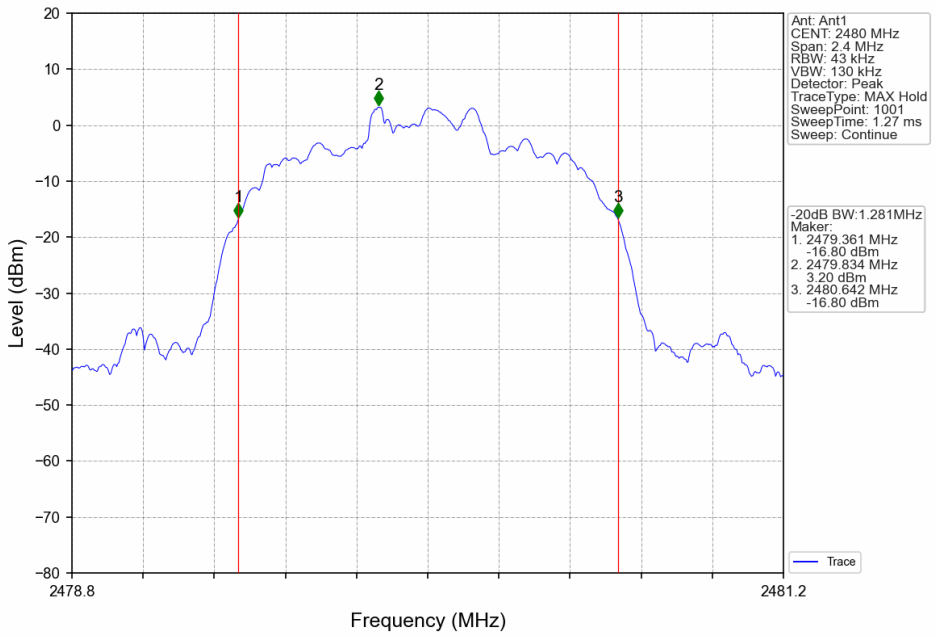
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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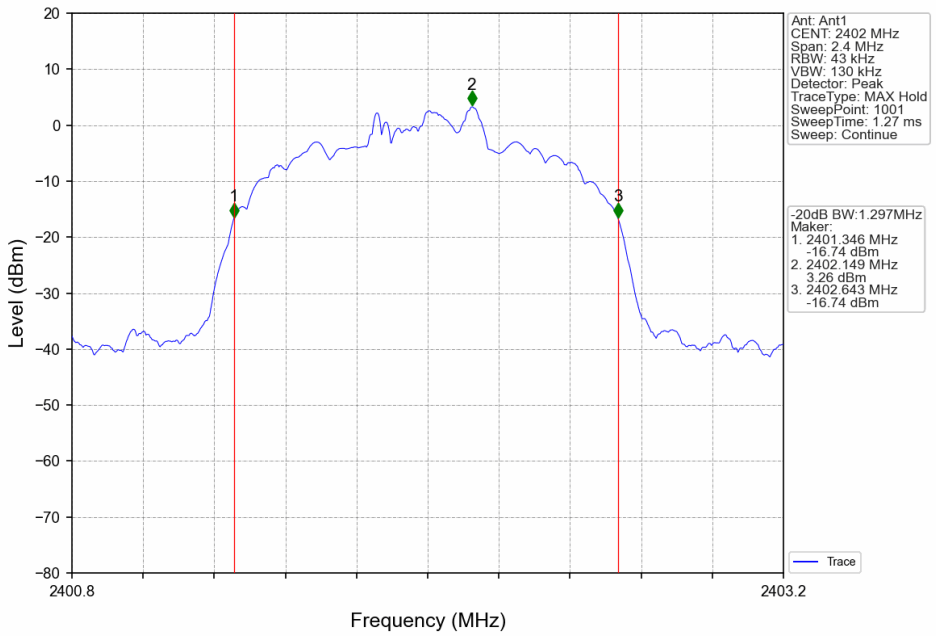
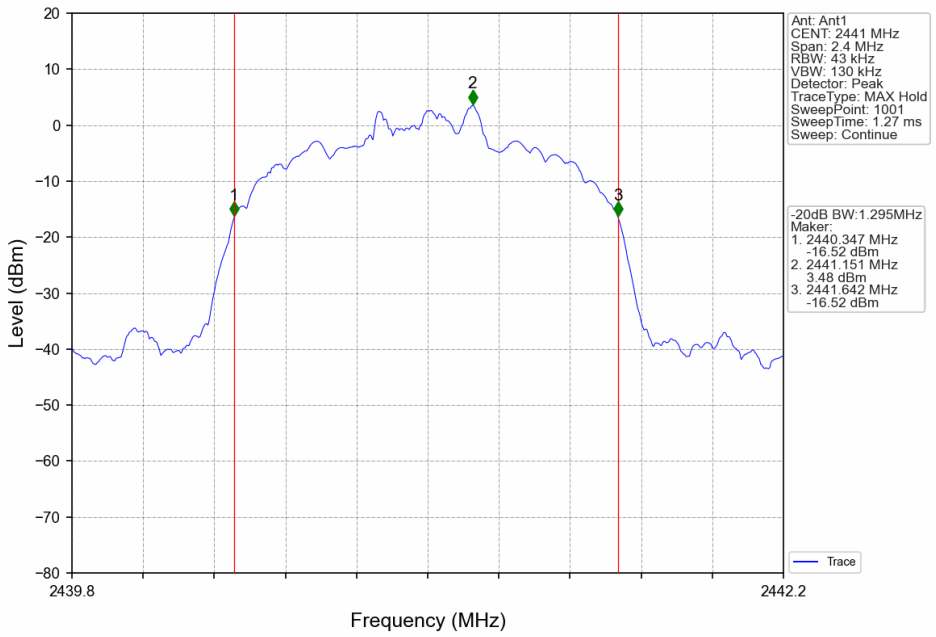
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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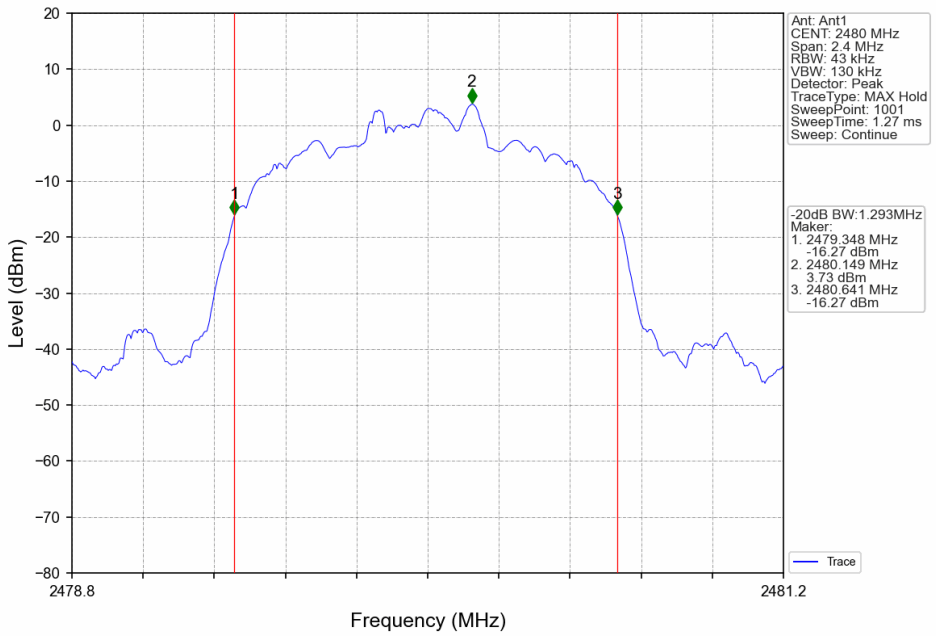
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



2. Maximum Conducted Output Power

2.1 Power

2.1.1 Test Result

Mode	TX Type	Frequency (MHz)	Packet Type	Maximum Peak Conducted Output Power (dBm)		Verdict
				ANT1	Limit	
GFSK	SISO	2402	DH5	6.61	<=30	Pass
		2441	DH5	6.88	<=30	Pass
		2480	DH5	7.09	<=30	Pass
Pi/4DQPSK	SISO	2402	2DH5	4.79	<=20.97	Pass
		2441	2DH5	5.00	<=20.97	Pass
		2480	2DH5	5.32	<=20.97	Pass
8DPSK	SISO	2402	3DH5	4.76	<=20.97	Pass
		2441	3DH5	4.99	<=20.97	Pass
		2480	3DH5	5.29	<=20.97	Pass
Note1: Antenna Gain: Ant1: 1.30dBi;						

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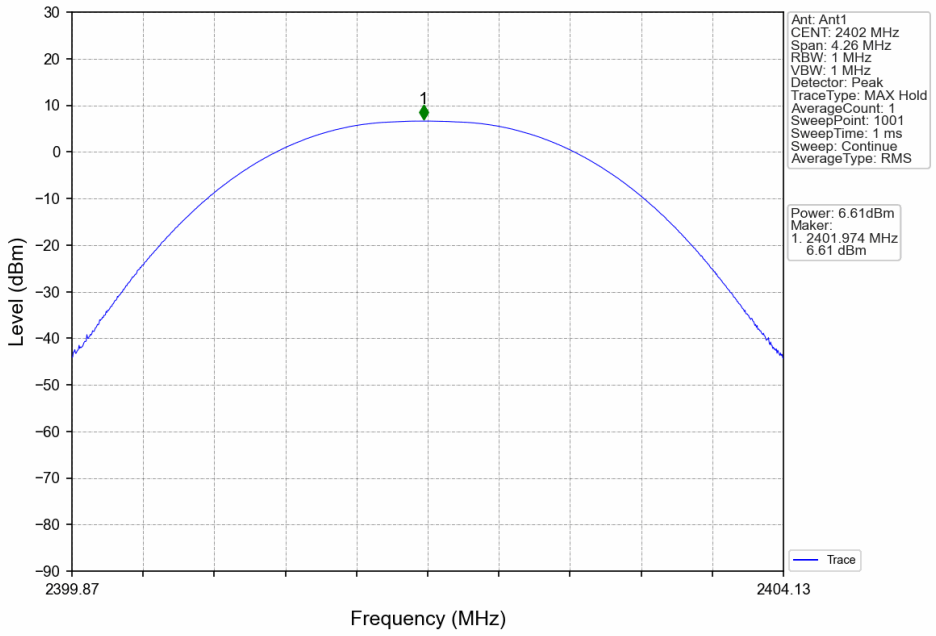
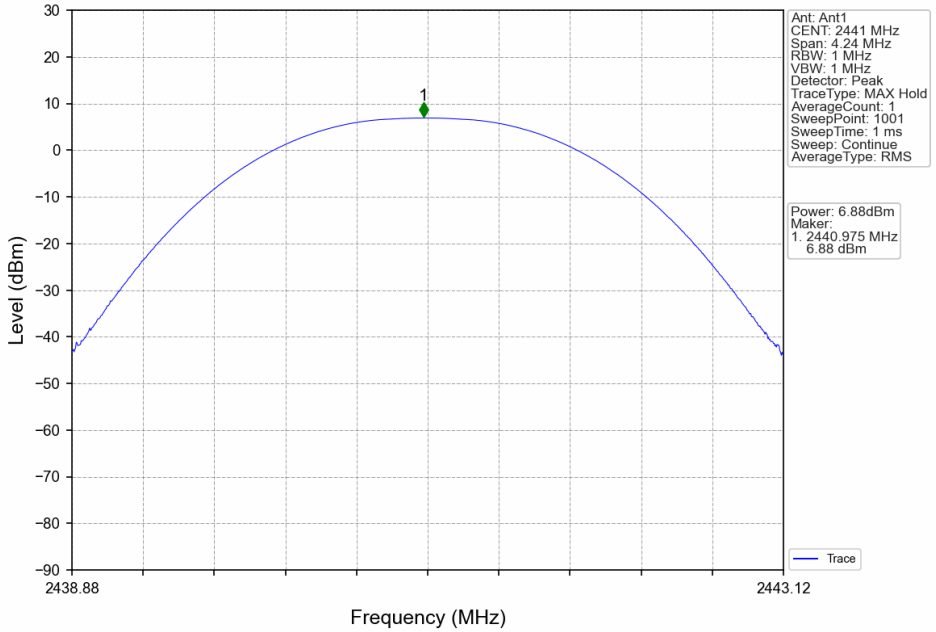
2.1.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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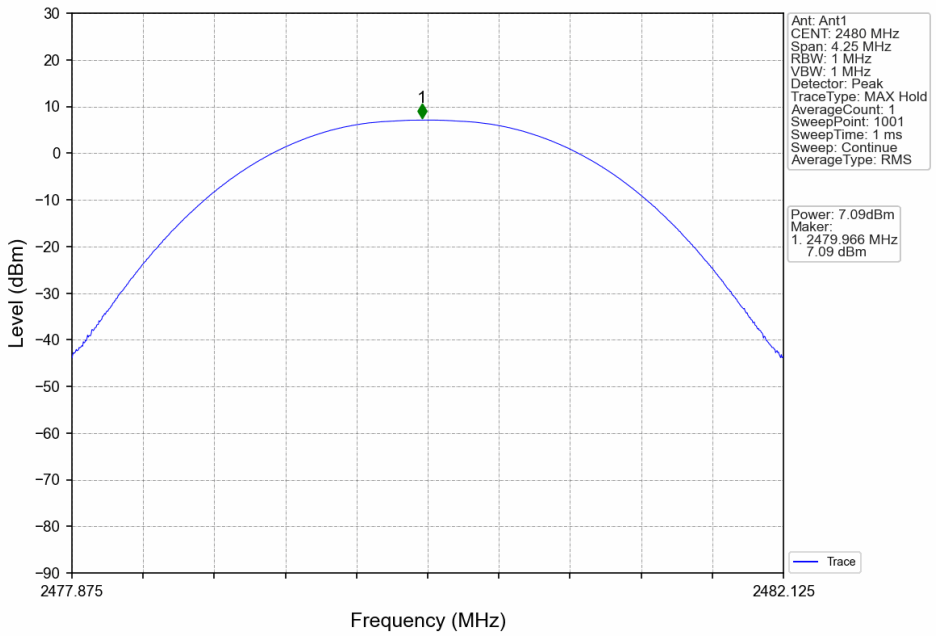
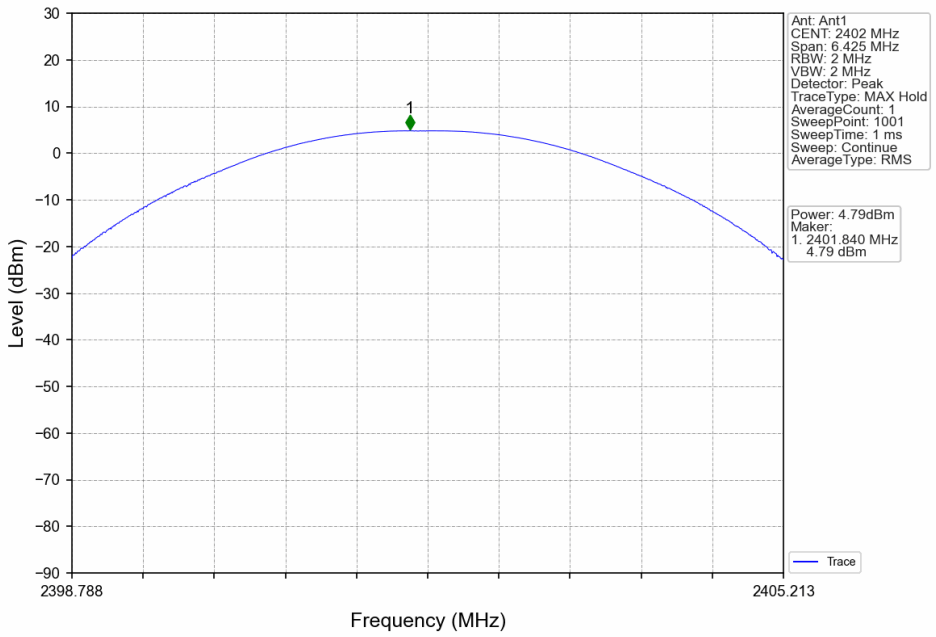
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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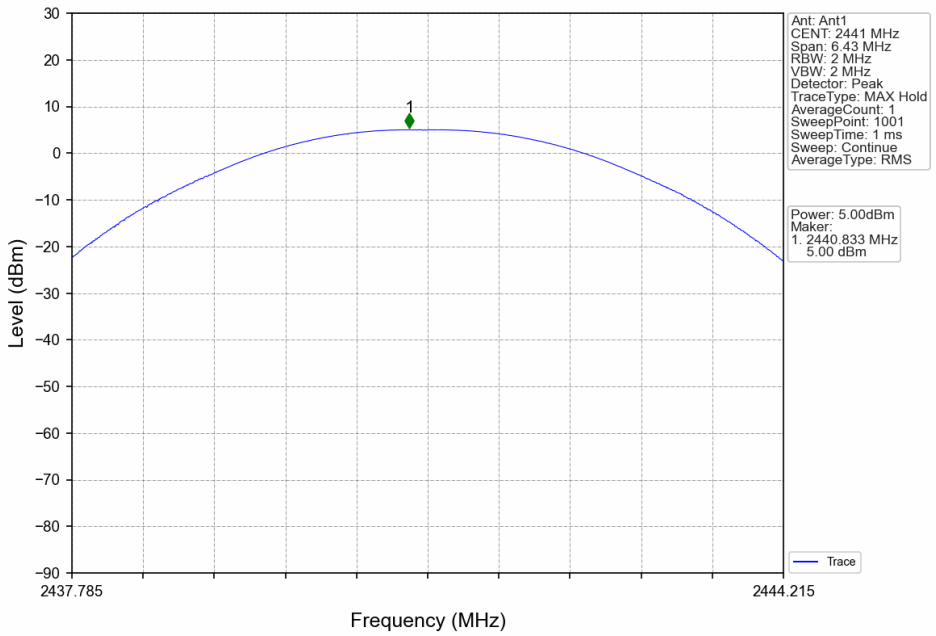
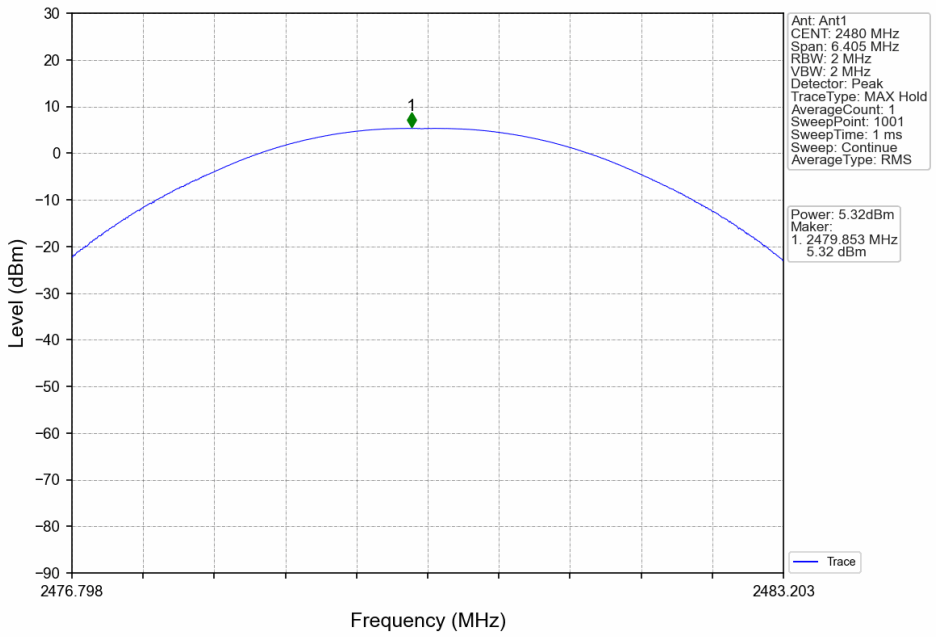
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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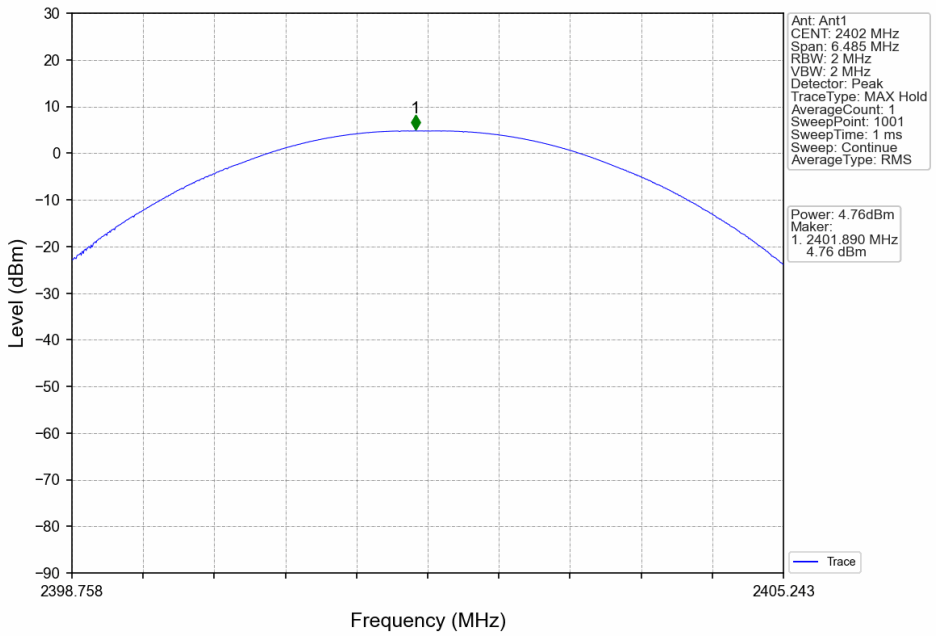
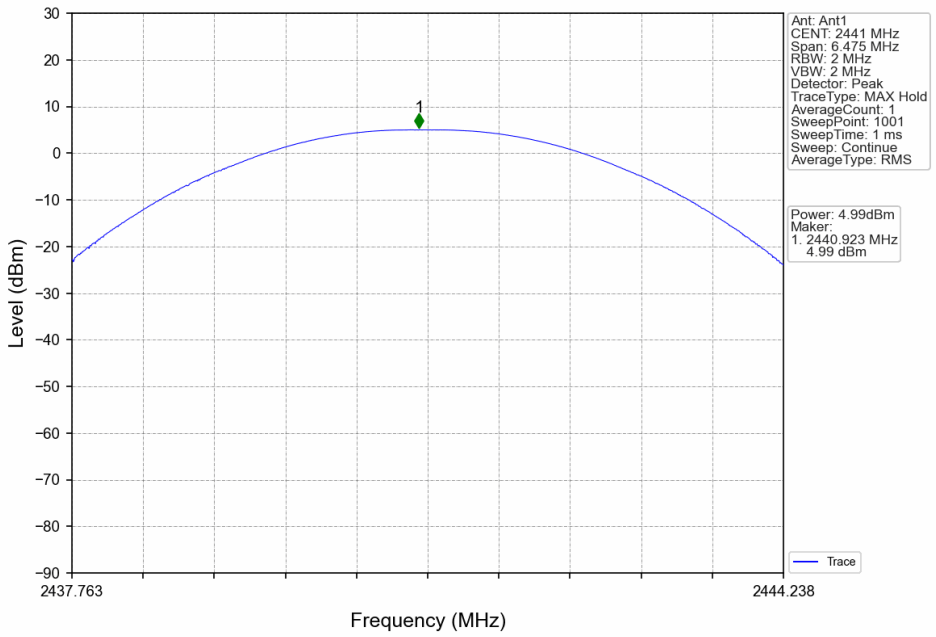
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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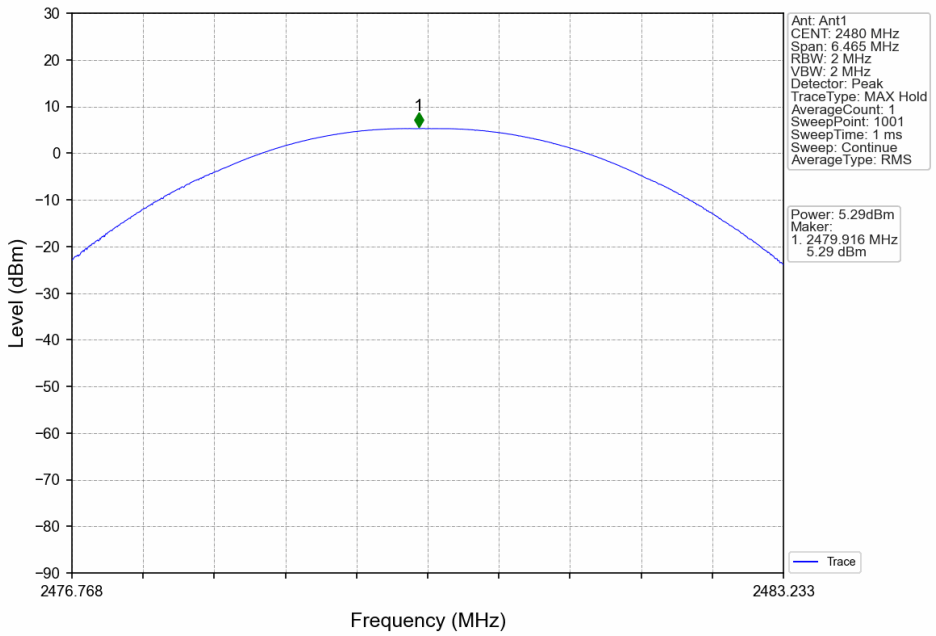
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



3. Carrier Frequency Separation

3.1 Ant1

3.1.1 Test Result

Ant1							
Mode	TX Type	Frequency (MHz)	Packet Type	Channel Separation (MHz)	20dB Bandwidth (MHz)	Limit (MHz)	Verdict
GFSK	SISO	HOPP	DH5	1.008	0.852	>=0.852	Pass
Pi/4DQPSK	SISO	HOPP	2DH5	0.998	1.286	>=0.857	Pass
8DPSK	SISO	HOPP	3DH5	1.001	1.297	>=0.865	Pass

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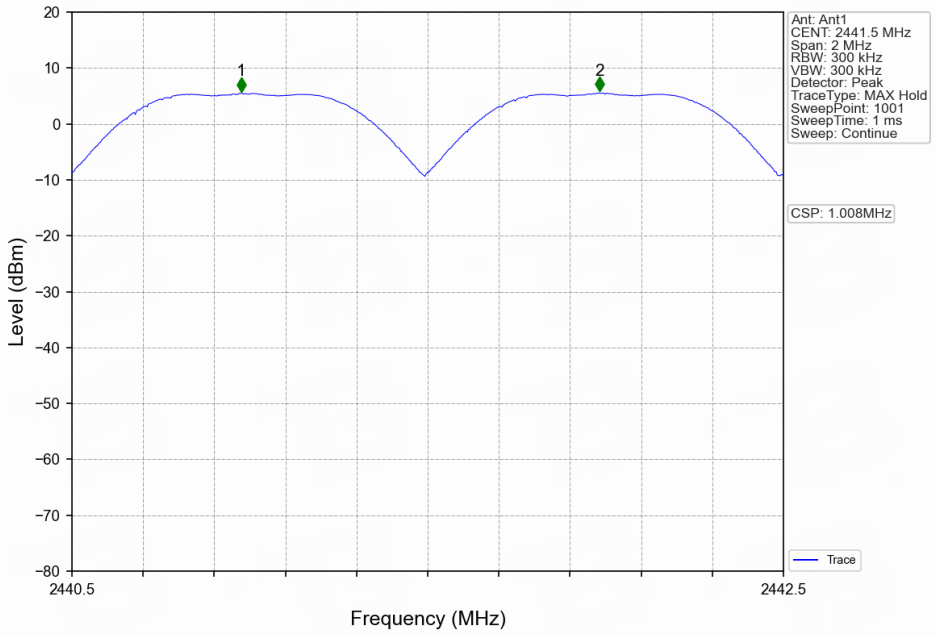
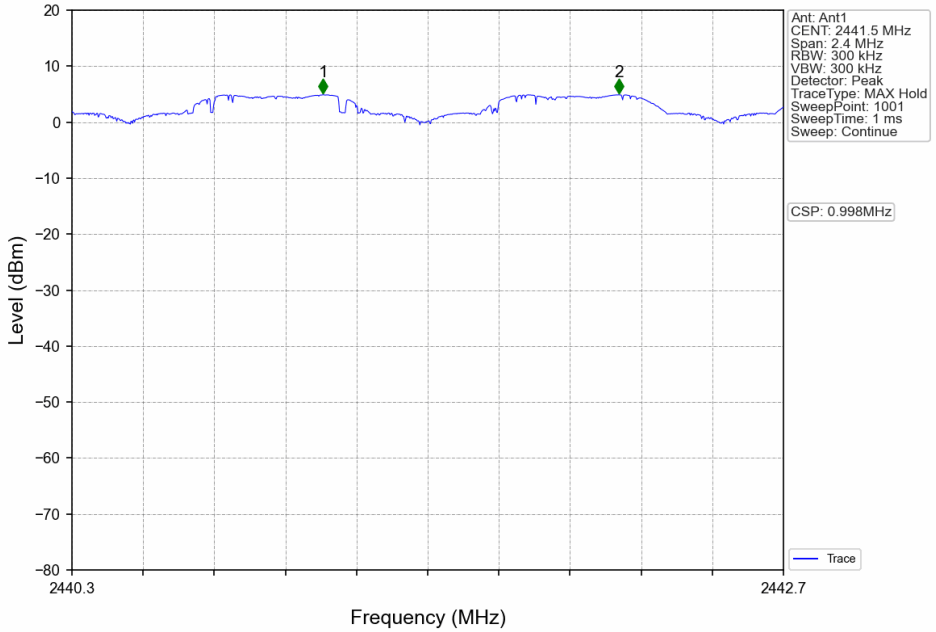
3.1.2 Test Graph

GFSK_DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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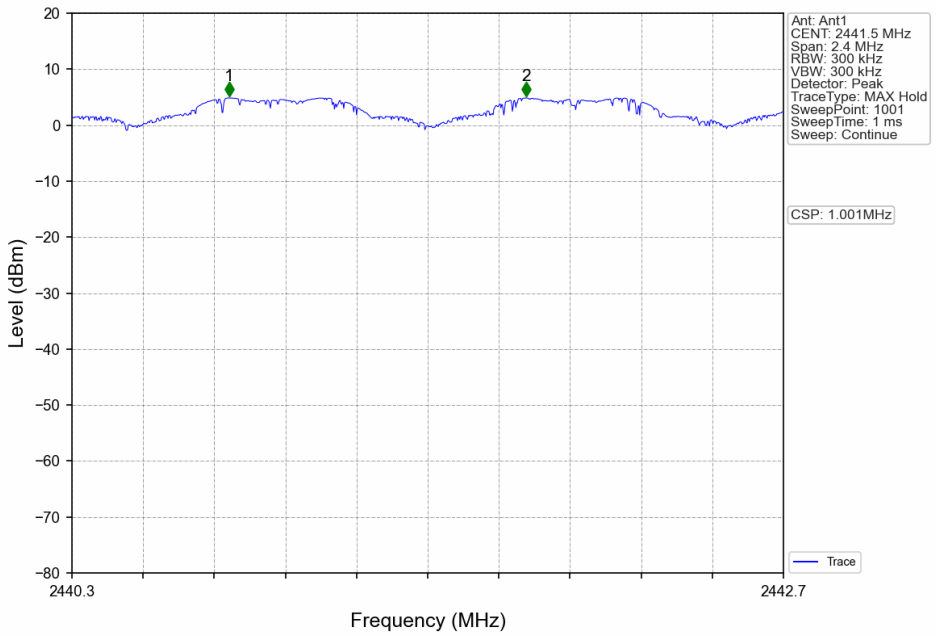
8DPSK_3DH5_HOPP_Ant1_NTNV



4. Number of Hopping Frequencies

4.1 HoppNum

4.1.1 Test Result

Mode	TX Type	Frequency (MHz)	Packet Type	Num of Hopping Frequencies		Verdict
				ANT1	Limit	
GFSK	SISO	HOPP	DH5	79	>=15	Pass
Pi/4DQPSK	SISO	HOPP	2DH5	79	>=15	Pass
8DPSK	SISO	HOPP	3DH5	79	>=15	Pass

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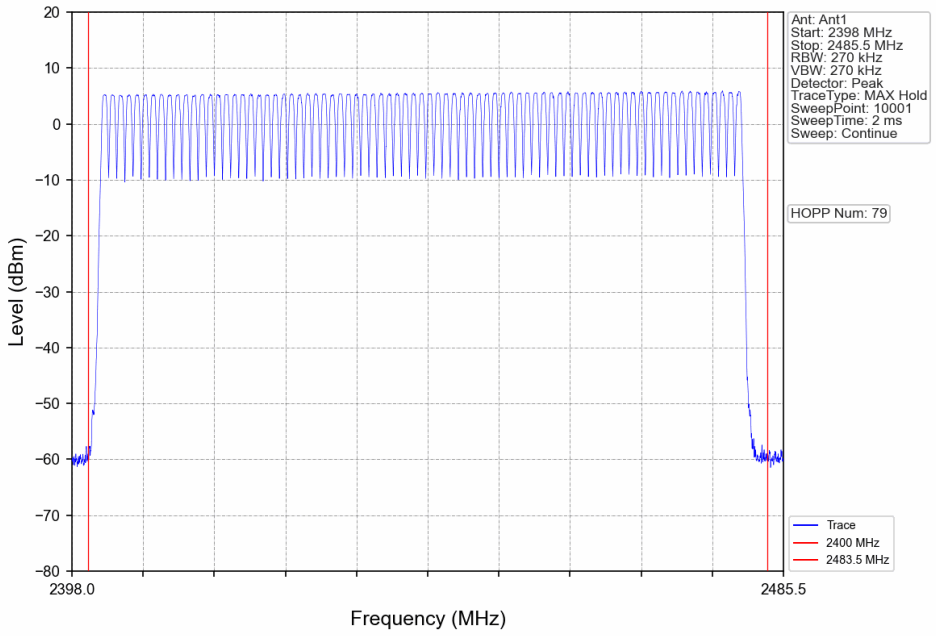
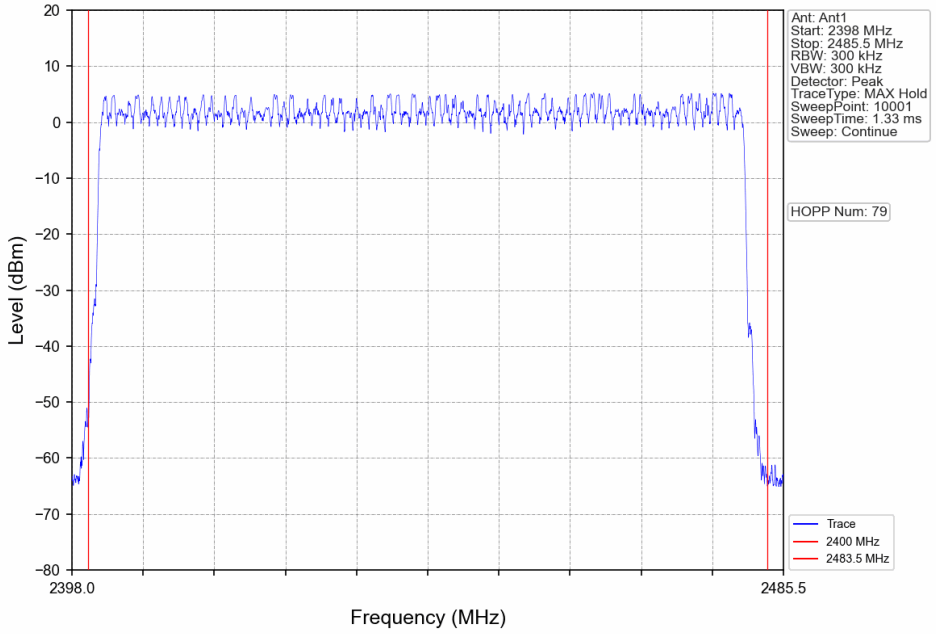
4.1.2 Test Graph

GFSK_DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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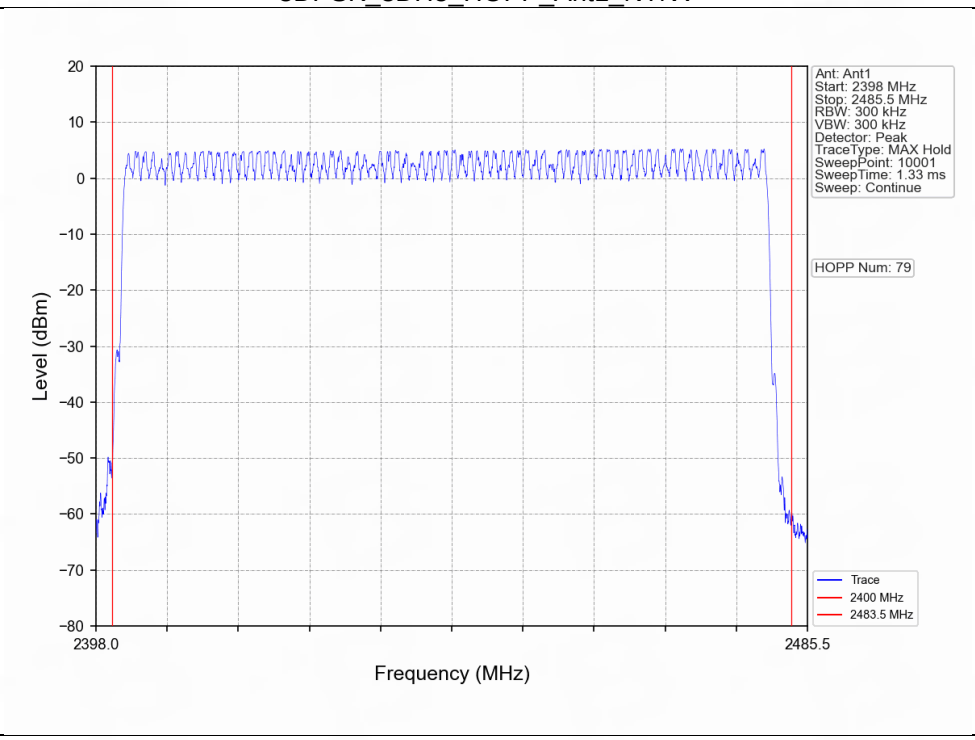
8DPSK_3DH5_HOPP_Ant1_NTNV



5. Time of Occupancy (Dwell Time)

5.1 Ant1

5.1.1 Test Result

Ant1									
Mode	TX Type	Frequency (MHz)	Packet Type	Duration of Single Pulse (ms)	Observation Period (s)	Num of Pulse in Observation Period	Dwell Time (ms)	Limit (ms)	Verdict
GFSK	SISO	HOPP	DH1	0.380	31.600	320	121.600	<=400	Pass
			DH3	1.650	31.600	160	264.000	<=400	Pass
			DH5	2.898	31.600	109	315.882	<=400	Pass
Pi/4DQPSK	SISO	HOPP	2DH1	0.386	31.600	320	123.520	<=400	Pass
			2DH3	1.640	31.600	153	250.920	<=400	Pass
			2DH5	2.900	31.600	100	290.000	<=400	Pass
8DPSK	SISO	HOPP	3DH1	0.402	31.600	320	128.640	<=400	Pass
			3DH3	1.638	31.600	160	262.080	<=400	Pass
			3DH5	2.904	31.600	110	319.440	<=400	Pass

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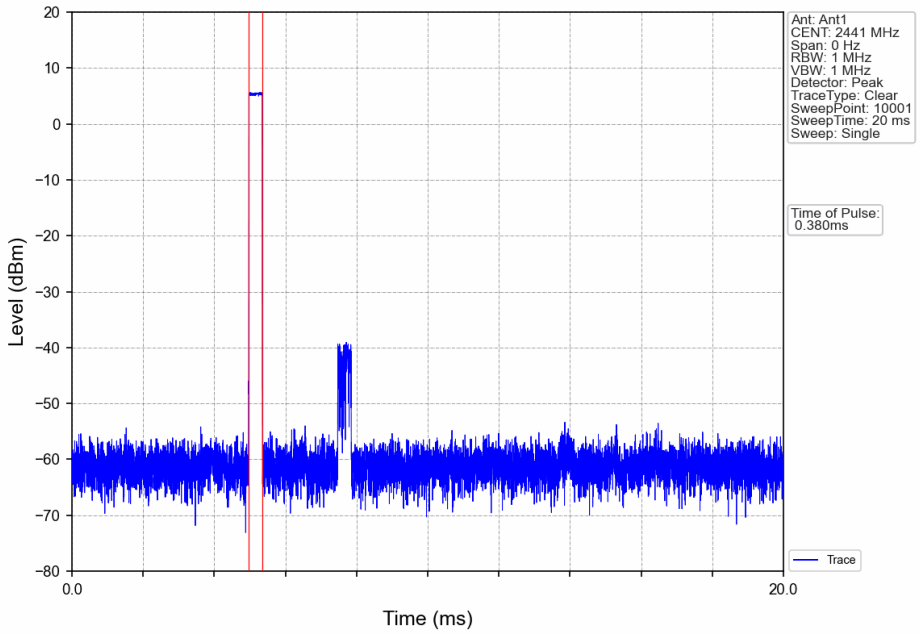
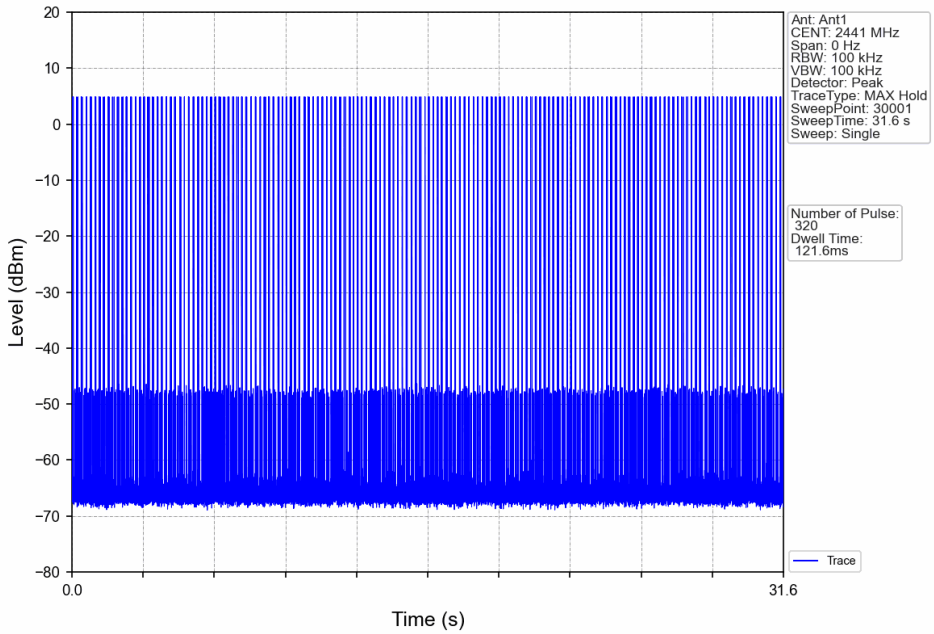
5.1.2 Test Graph

GFSK_DH1_HOPP_Ant1_NTNV



GFSK_DH1_HOPP_Ant1_NTNV



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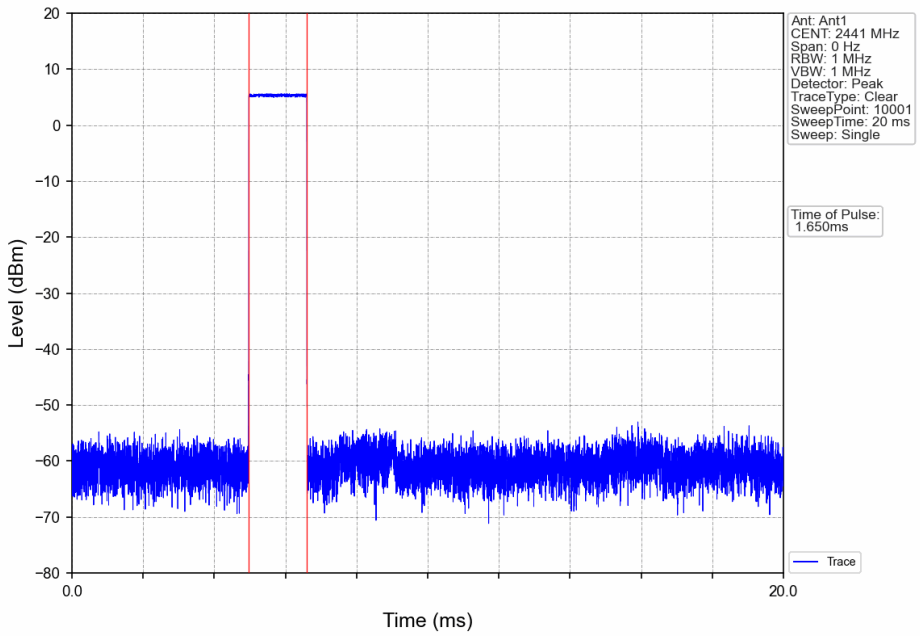
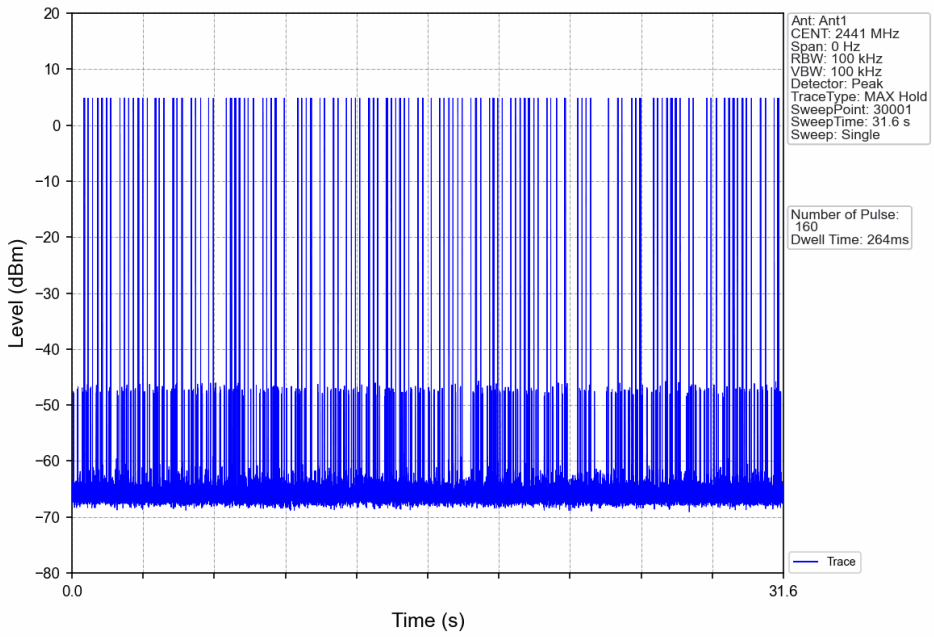
GFSK_DH3_HOPP_Ant1_NTNV



GFSK_DH3_HOPP_Ant1_NTNV



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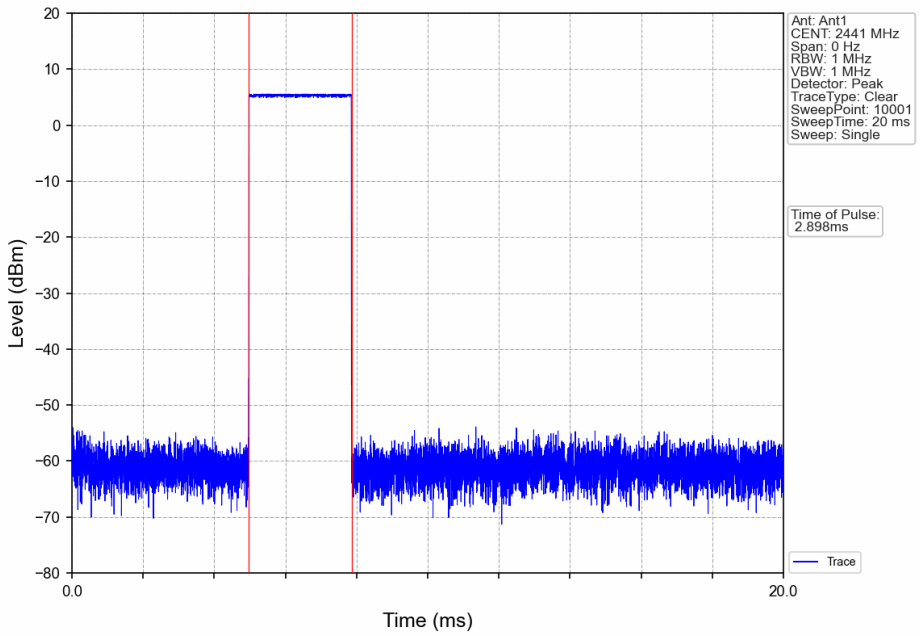
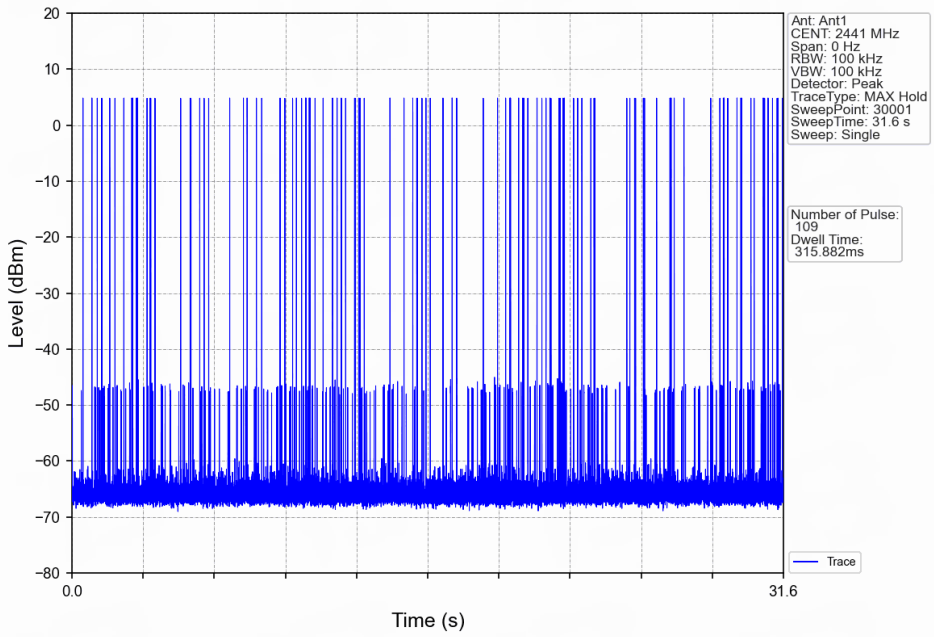
GFSK_DH5_HOPP_Ant1_NTNV



GFSK_DH5_HOPP_Ant1_NTNV



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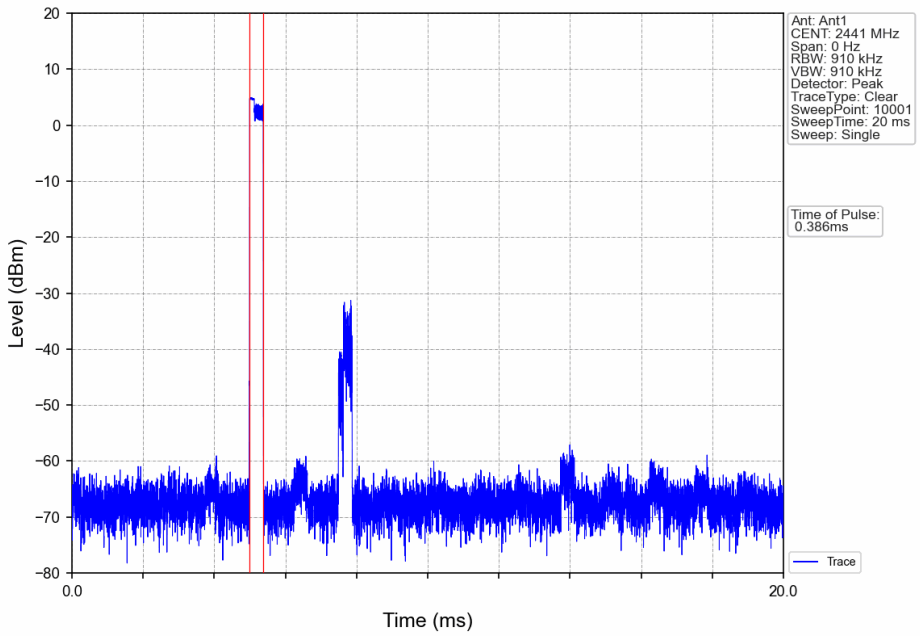
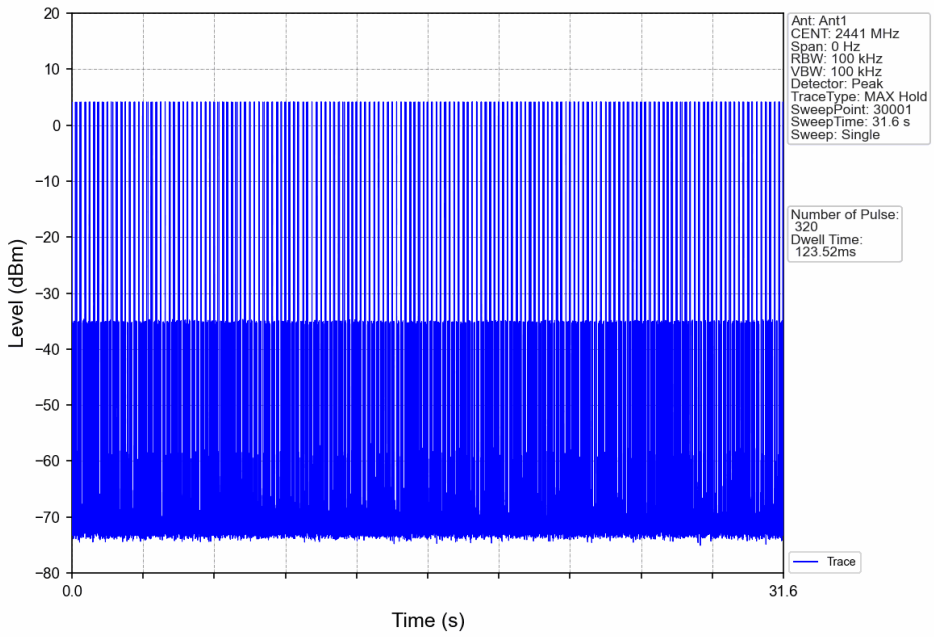
Pi/4DQPSK_2DH1_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH1_HOPP_Ant1_NTNV



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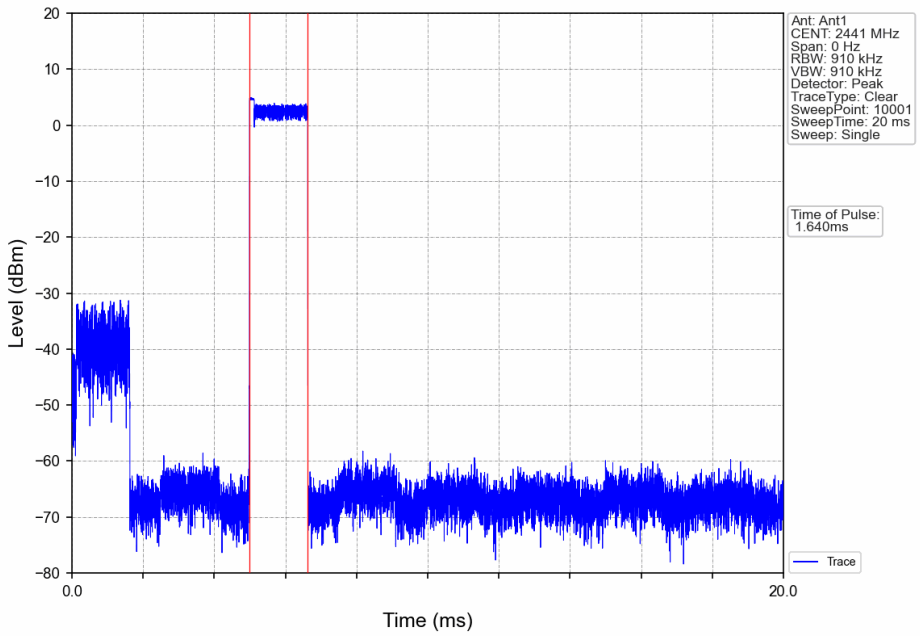
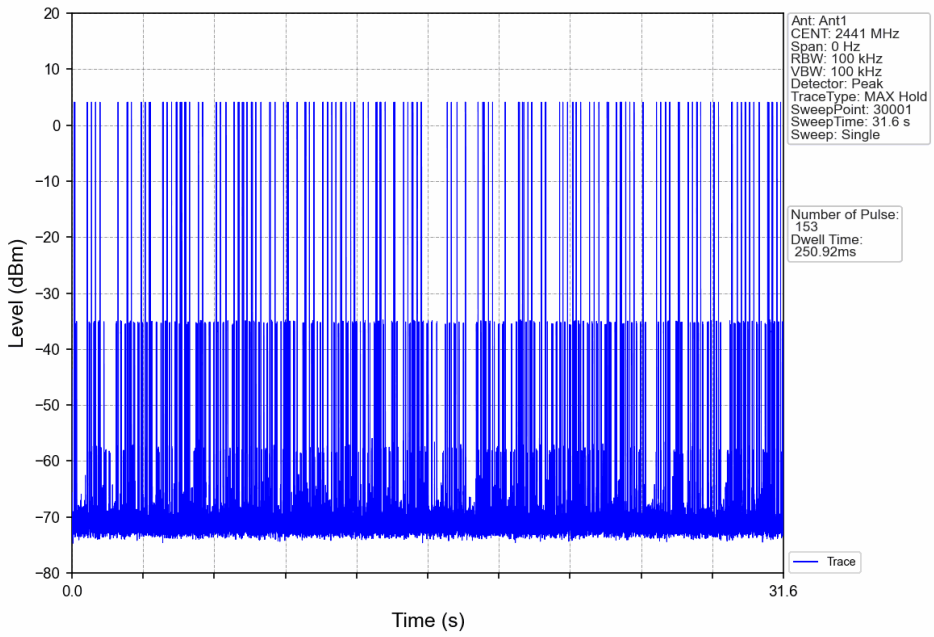
Pi/4DQPSK_2DH3_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH3_HOPP_Ant1_NTNV



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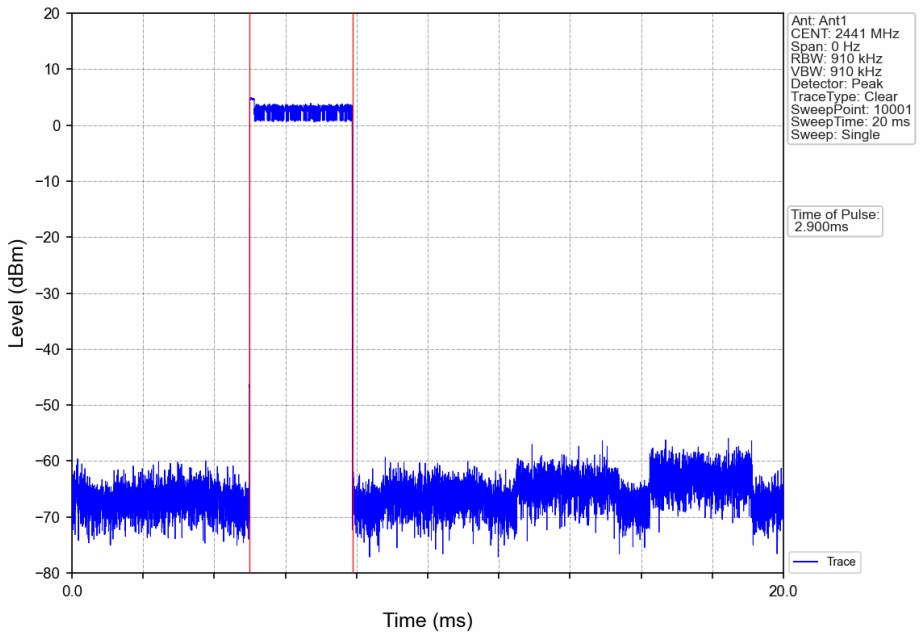
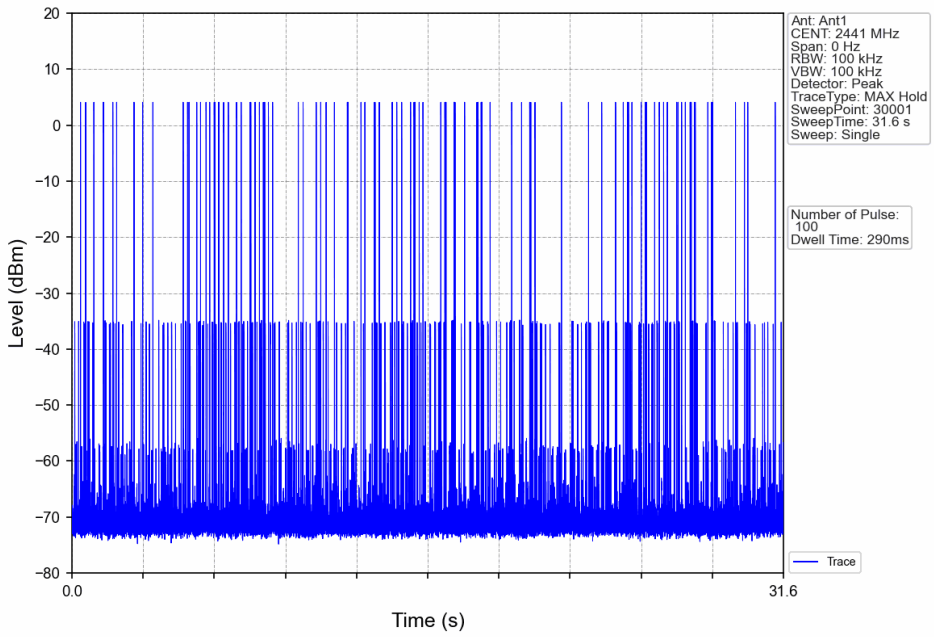
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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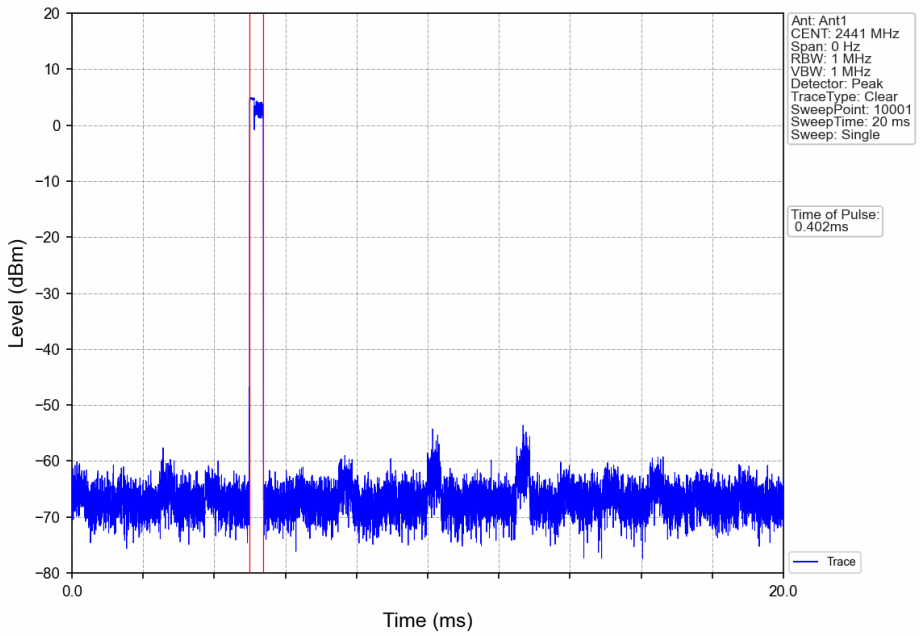
8DPSK_3DH1_HOPP_Ant1_NTNV



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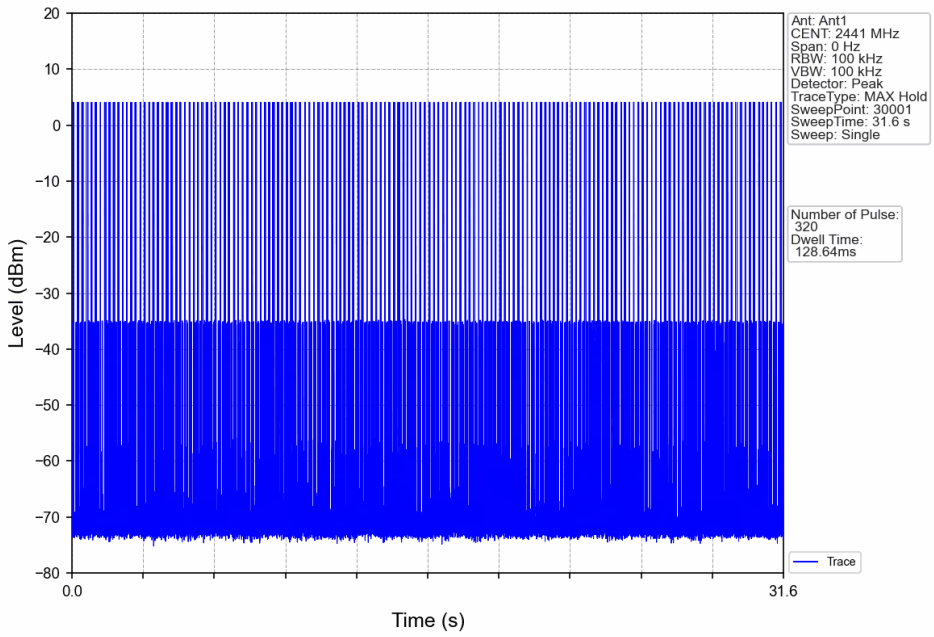

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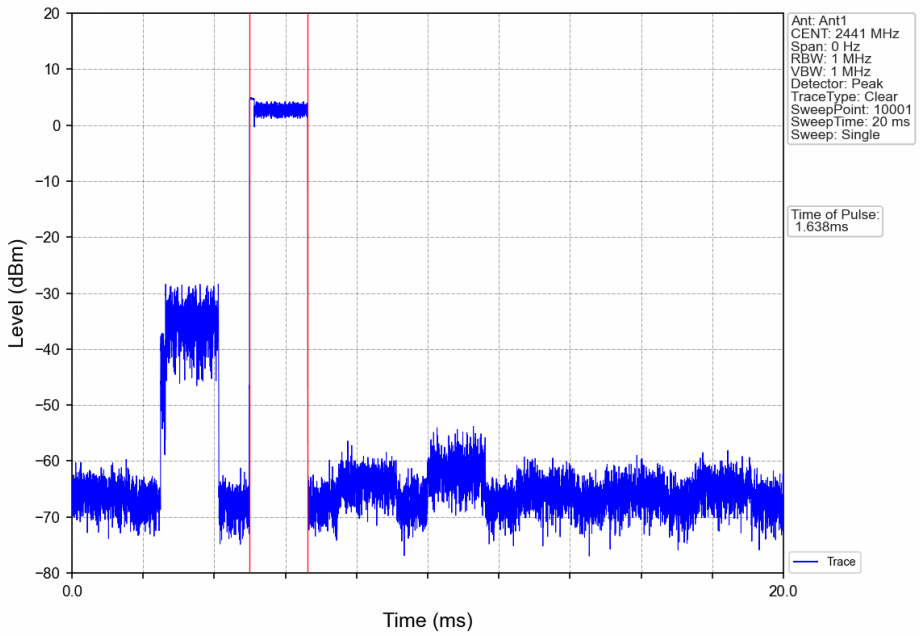
8DPSK_3DH3_HOPP_Ant1_NTNV



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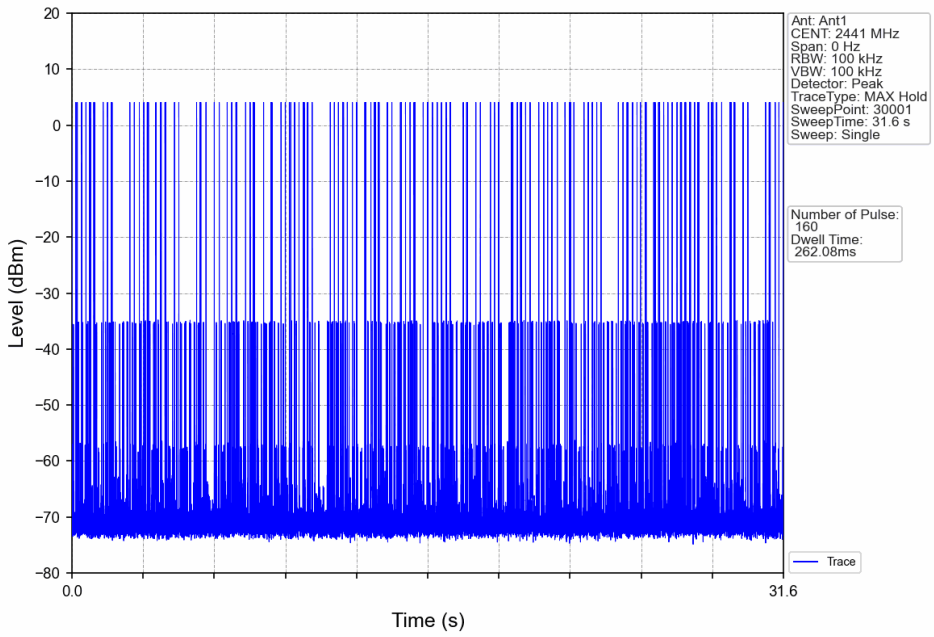

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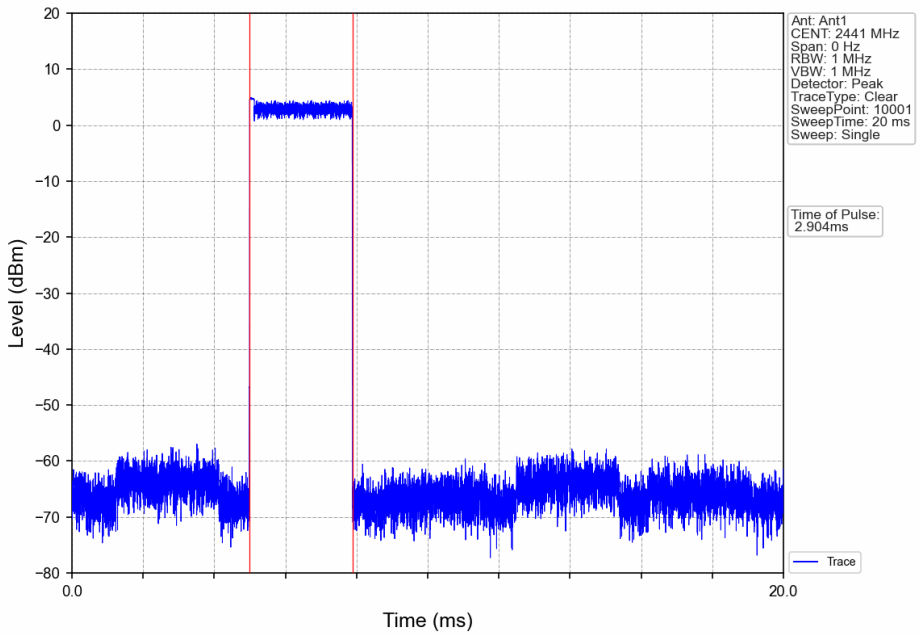
8DPSK_3DH5_HOPP_Ant1_NTNV



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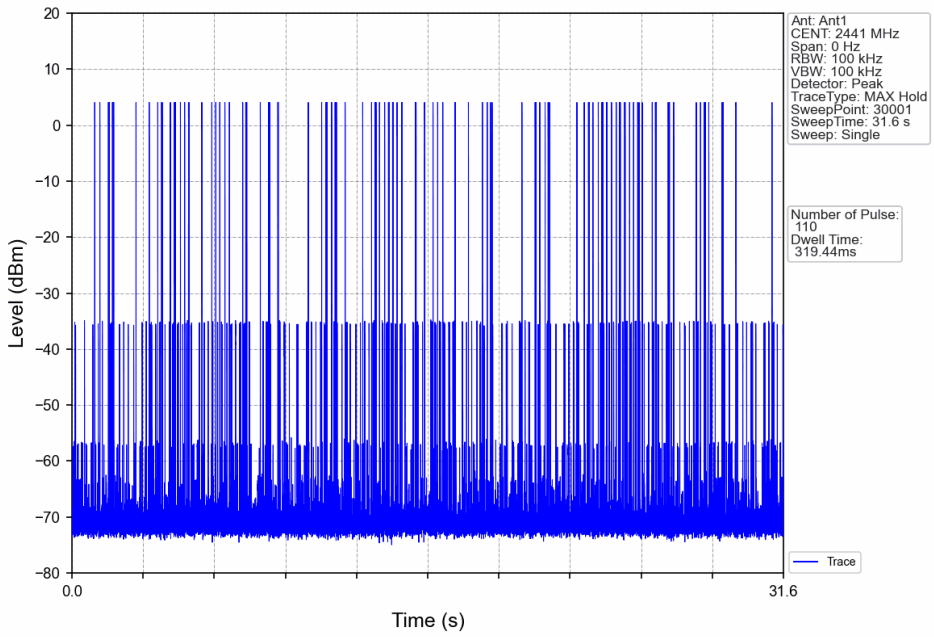

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6. Unwanted Emissions In Non-restricted Frequency Bands

6.1 Ref

6.1.1 Test Result

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	Level of Reference (dBm)
GFSK	SISO	2402	DH5	1	6.34
		2441	DH5	1	6.59
		2480	DH5	1	6.76
Pi/4DQPSK	SISO	2402	2DH5	1	4.52
		2441	2DH5	1	4.84
		2480	2DH5	1	5.13
8DPSK	SISO	2402	3DH5	1	4.61
		2441	3DH5	1	4.84
		2480	3DH5	1	4.98
Note1: Refer to FCC Part 15.247 (d) and ANSI C63.10-2020, the channel contains the maximum PSD level was used to establish the reference level.					

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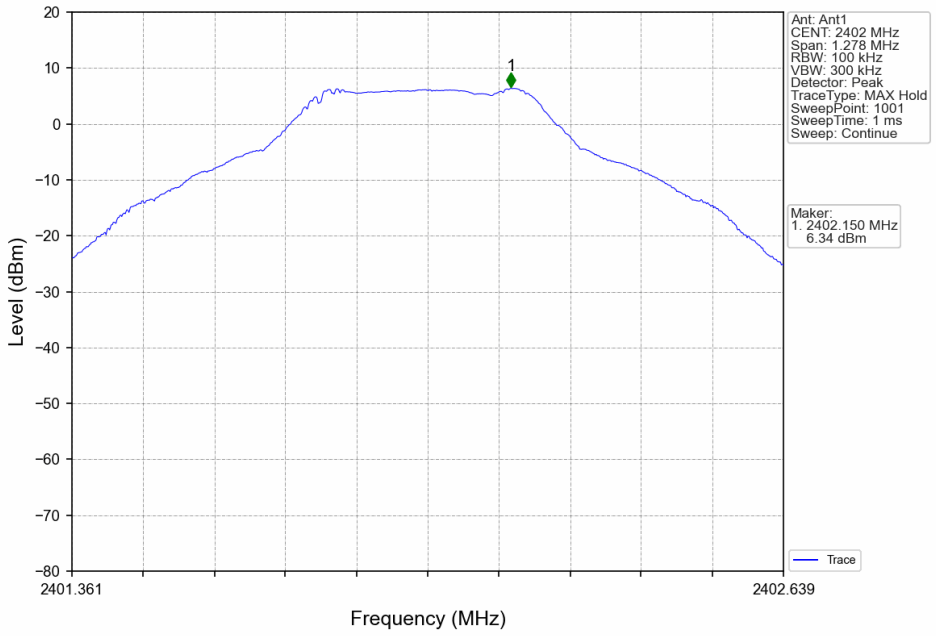
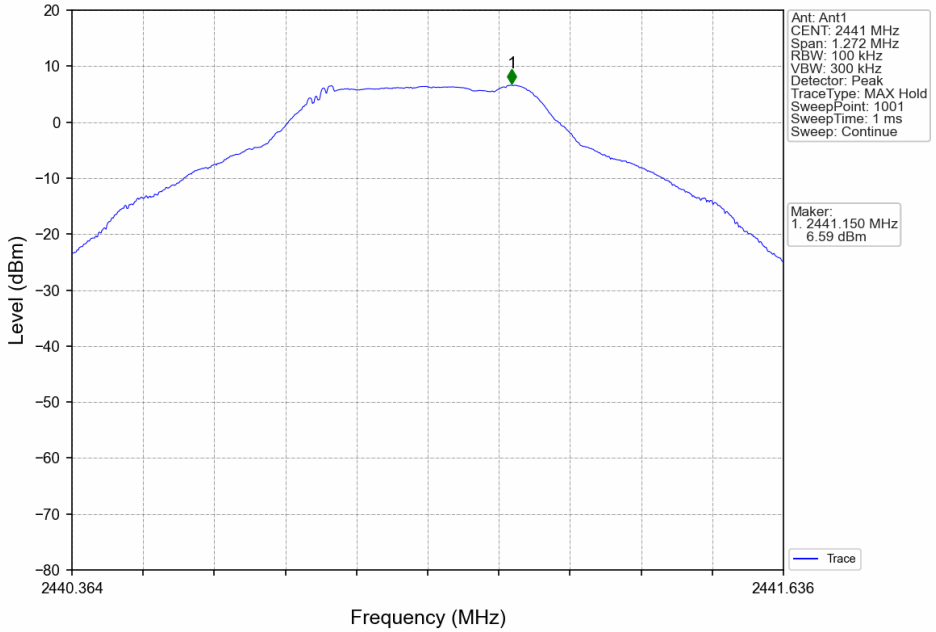
6.1.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_MCH_2441MHz_Ant1_NTNV



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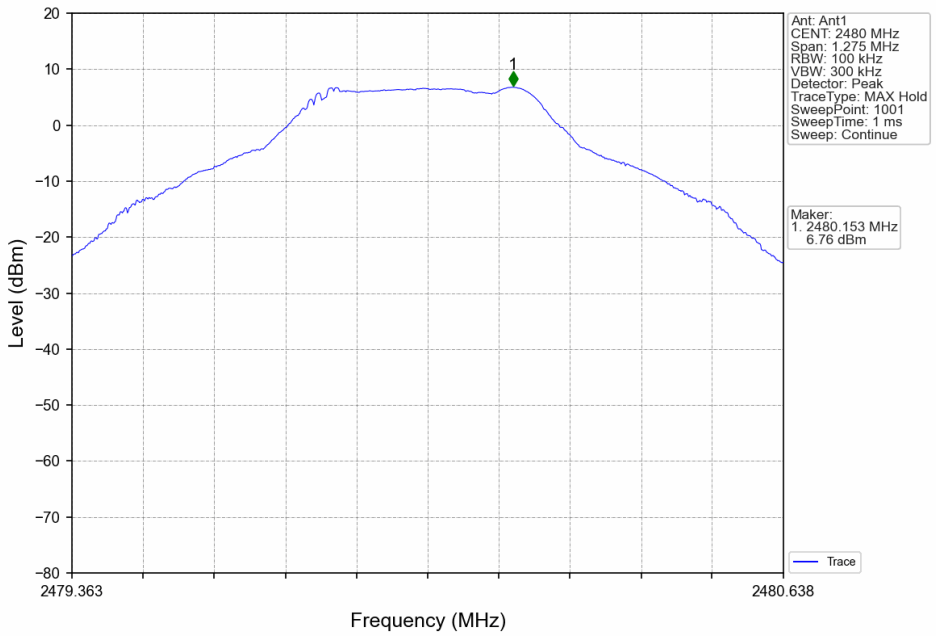
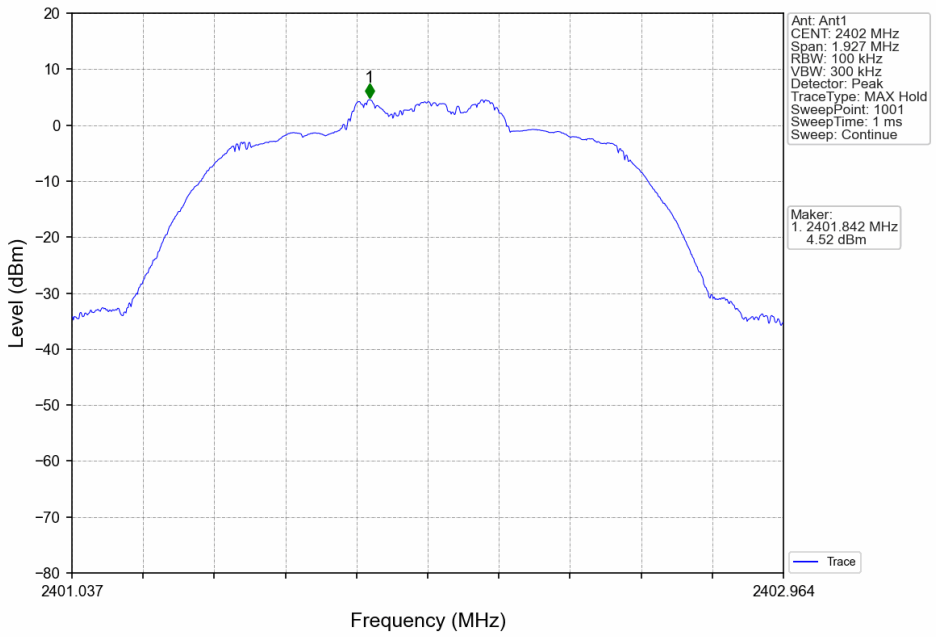
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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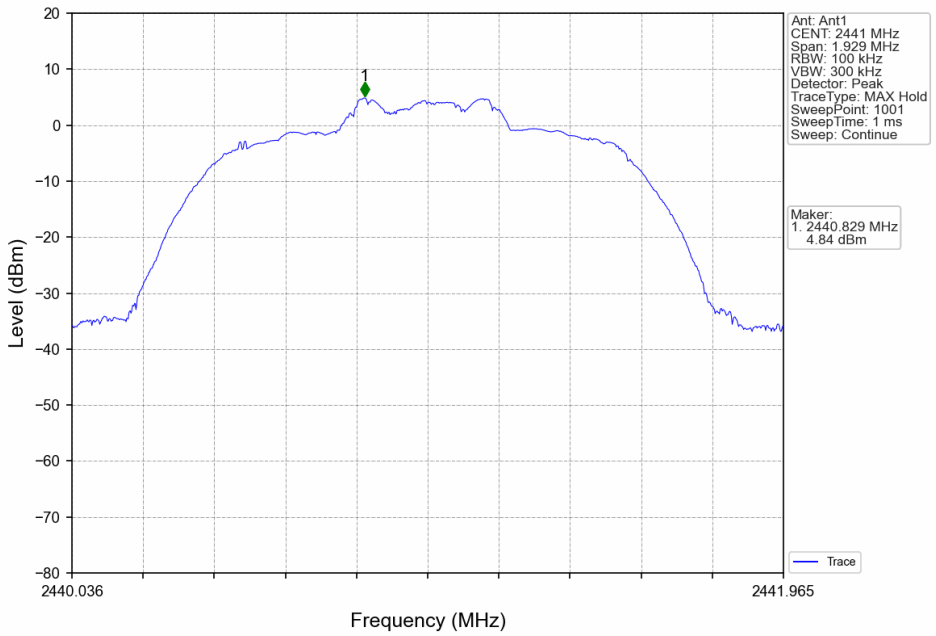
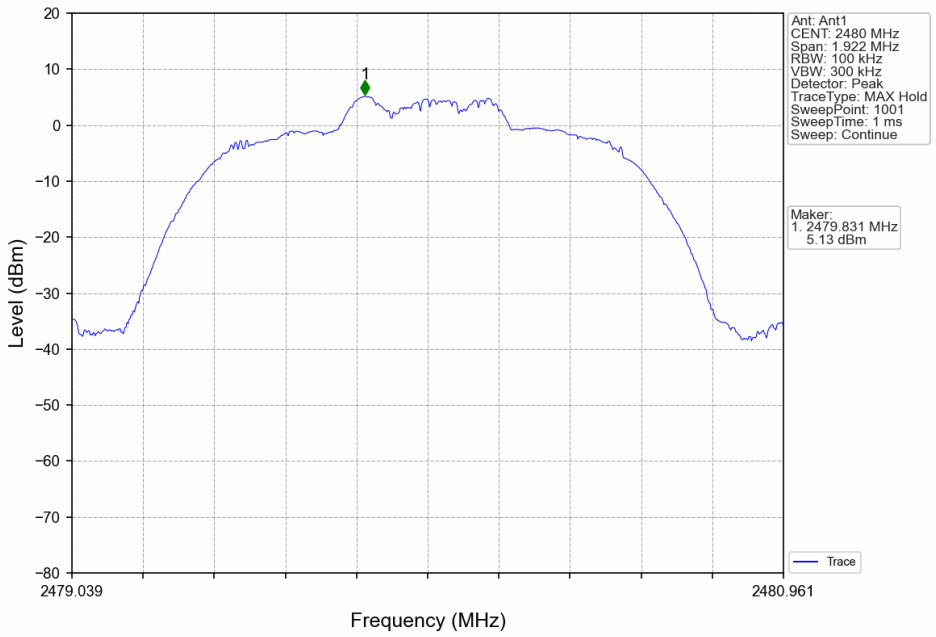
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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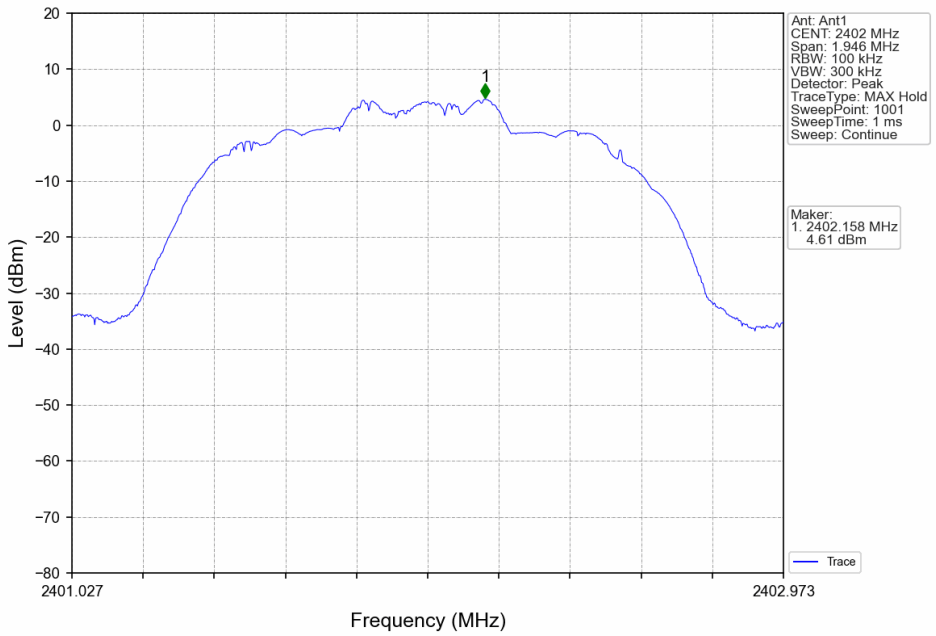
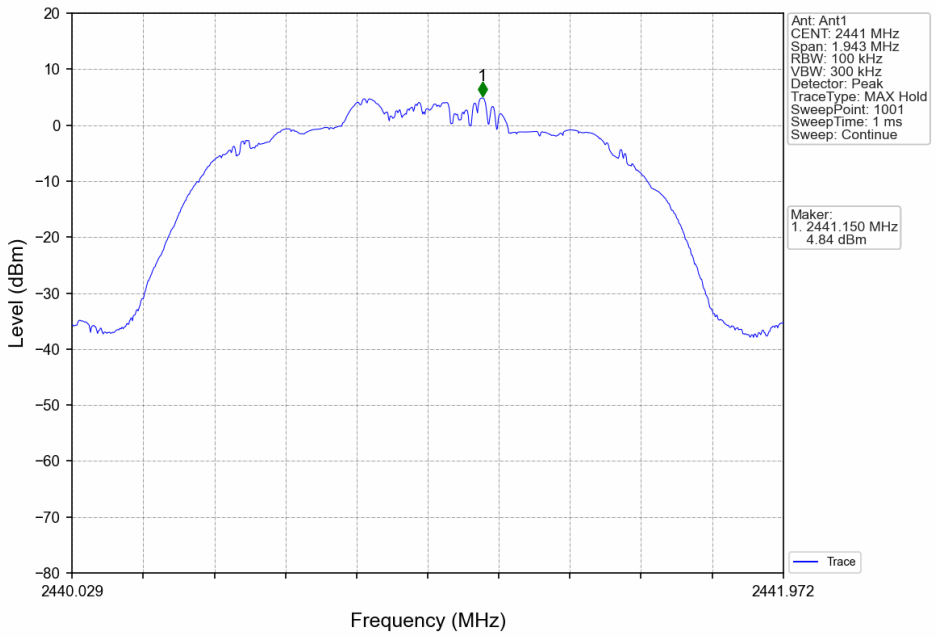
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



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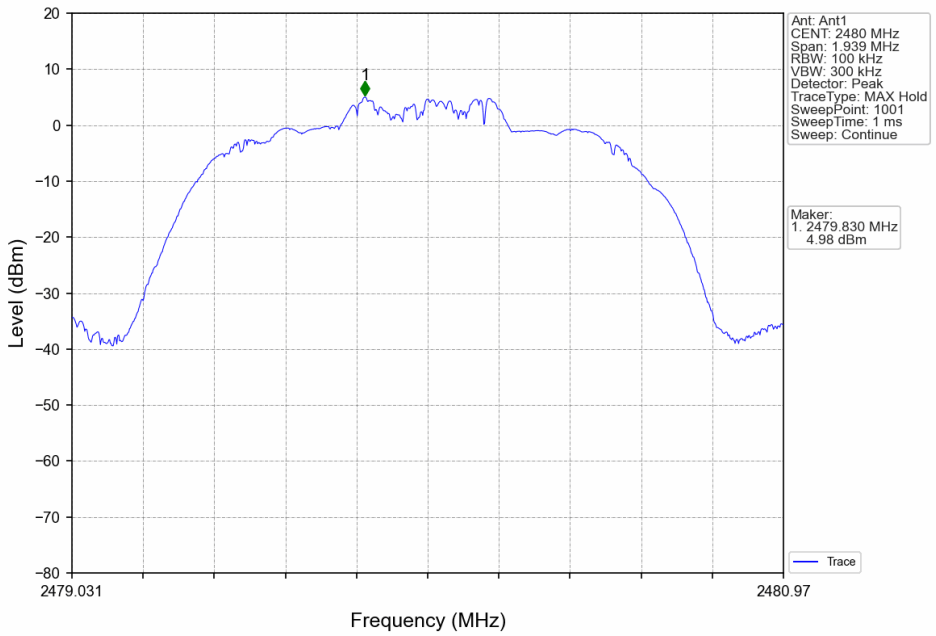
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



6.2 CSE

6.2.1 Test Result

Mode	TX Type	Frequency (MHz)	Packet Type	ANT	Measure	Level of Reference (dBm)	Limit (dBm)	Verdict
GFSK	SISO	2402	DH5	1	-52.23	6.76	-13.24	Pass
		2441	DH5	1	-52.98	6.76	-13.24	Pass
		2480	DH5	1	-51.32	6.76	-13.24	Pass
		HOPP	DH5	1	-63.53	6.76	-13.24	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	-54.29	5.13	-14.87	Pass
		2441	2DH5	1	-57.91	5.13	-14.87	Pass
		2480	2DH5	1	-53.75	5.13	-14.87	Pass
		HOPP	2DH5	1	-57.45	5.13	-14.87	Pass
8DPSK	SISO	2402	3DH5	1	-54.61	4.98	-15.02	Pass
		2441	3DH5	1	-54.20	4.98	-15.02	Pass
		2480	3DH5	1	-53.59	4.98	-15.02	Pass
		HOPP	3DH5	1	-59.03	4.98	-15.02	Pass
	Note1: Refer to FCC Part 15.247 (d) and ANSI C63.10-2020, the channel contains the maximum PSD level was used to establish the reference level.							

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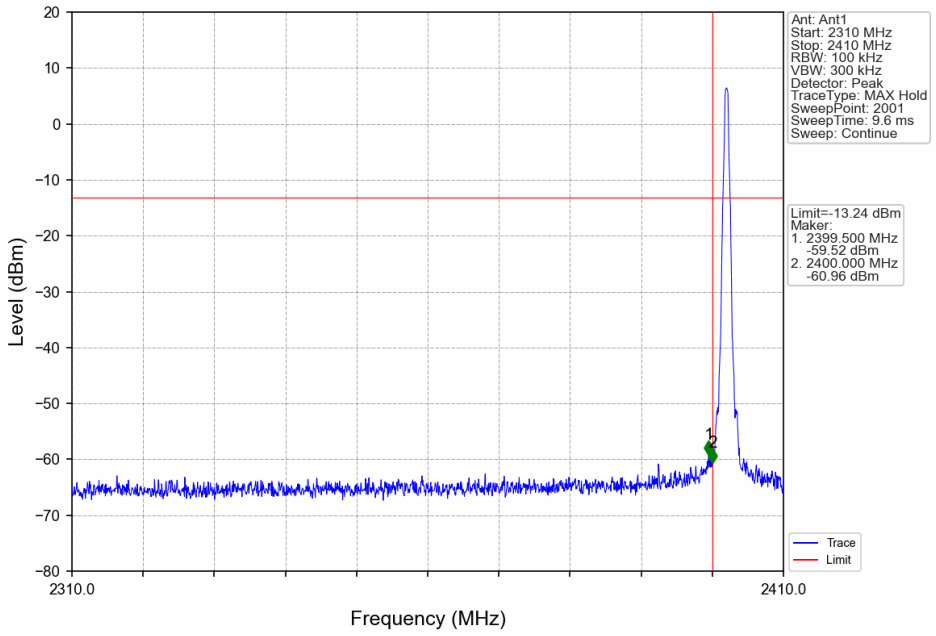
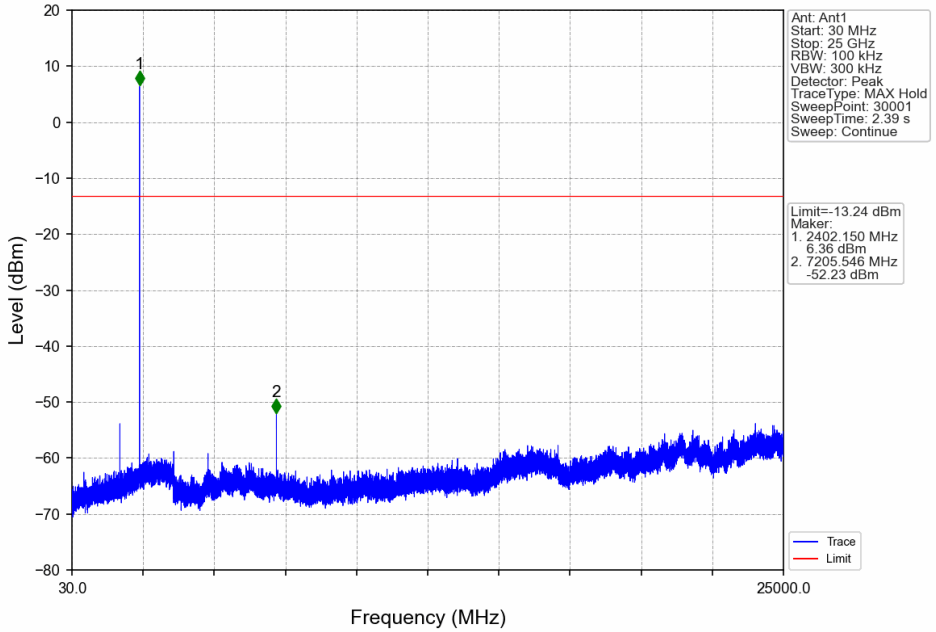
6.2.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



GFSK_DH5_LCH_2402MHz_Ant1_NTNV



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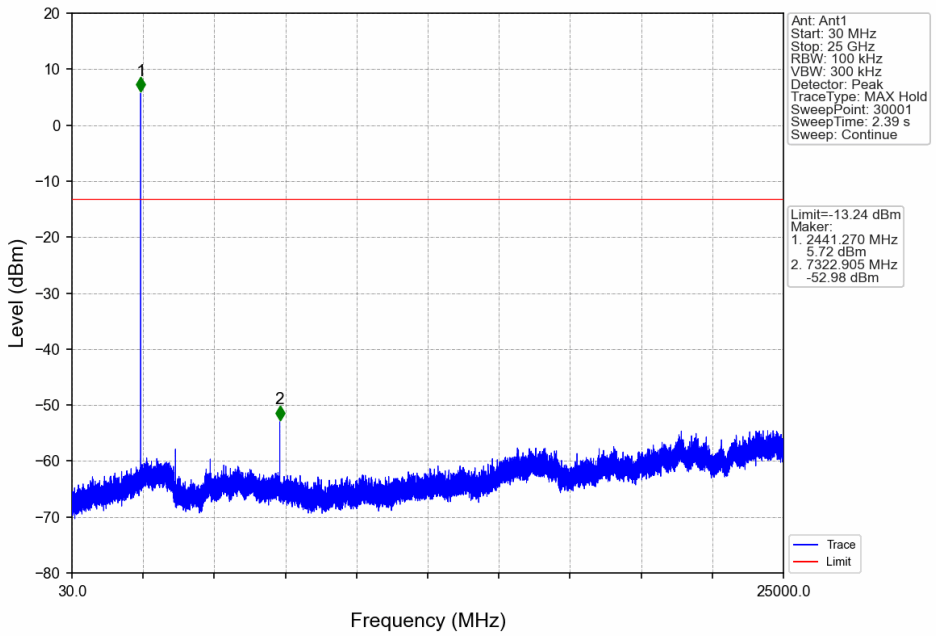
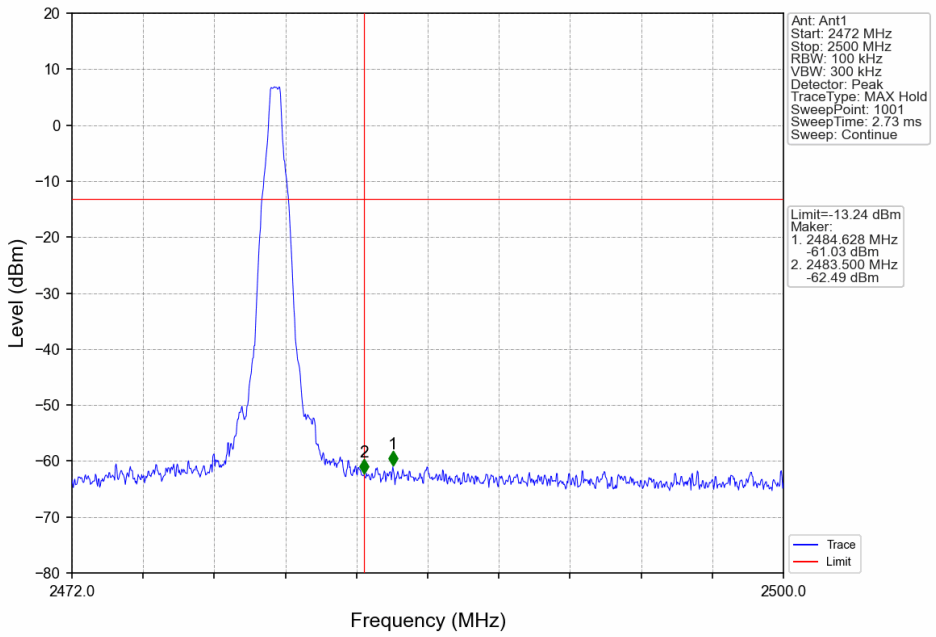
GFSK_DH5_MCH_2441MHz_Ant1_NTNV



GFSK_DH5_HCH_2480MHz_Ant1_NTNV



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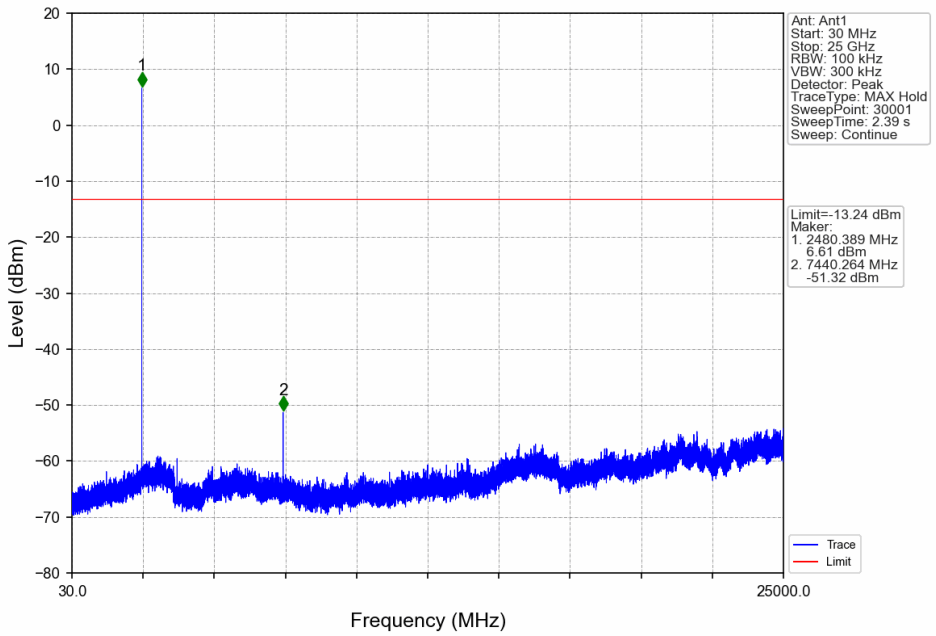
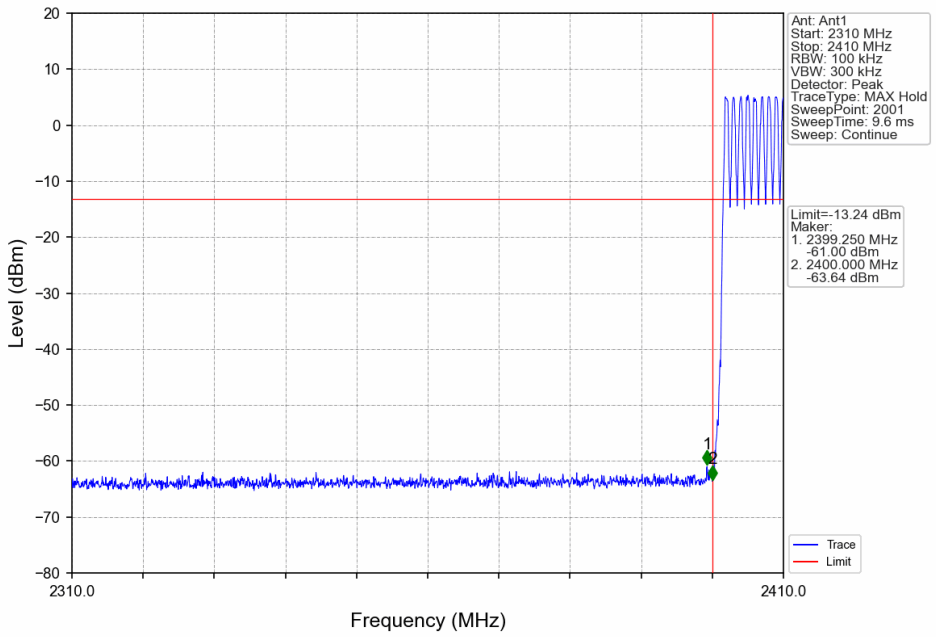
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



GFSK_DH5_HOPP_Ant1_NTNV



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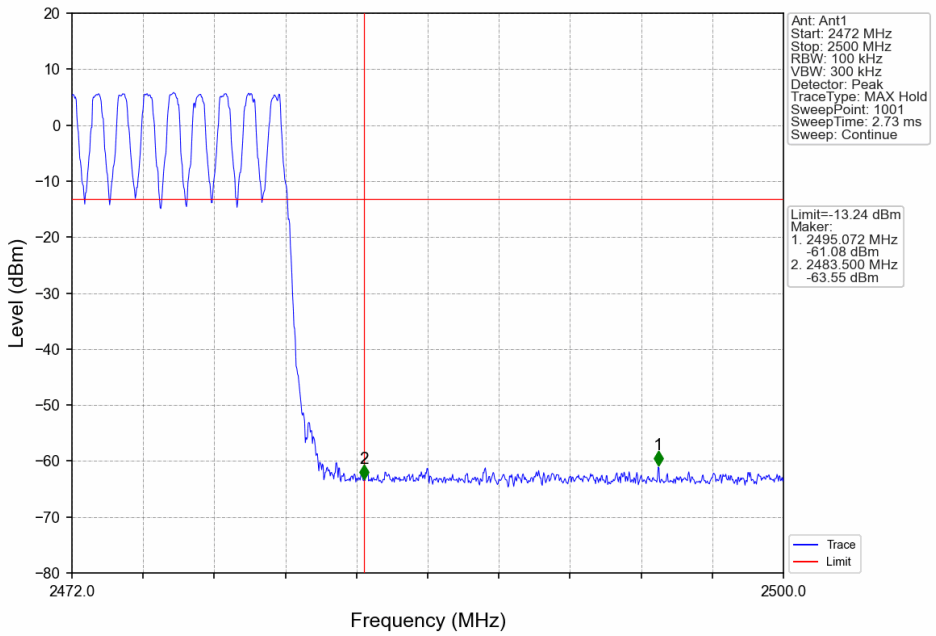
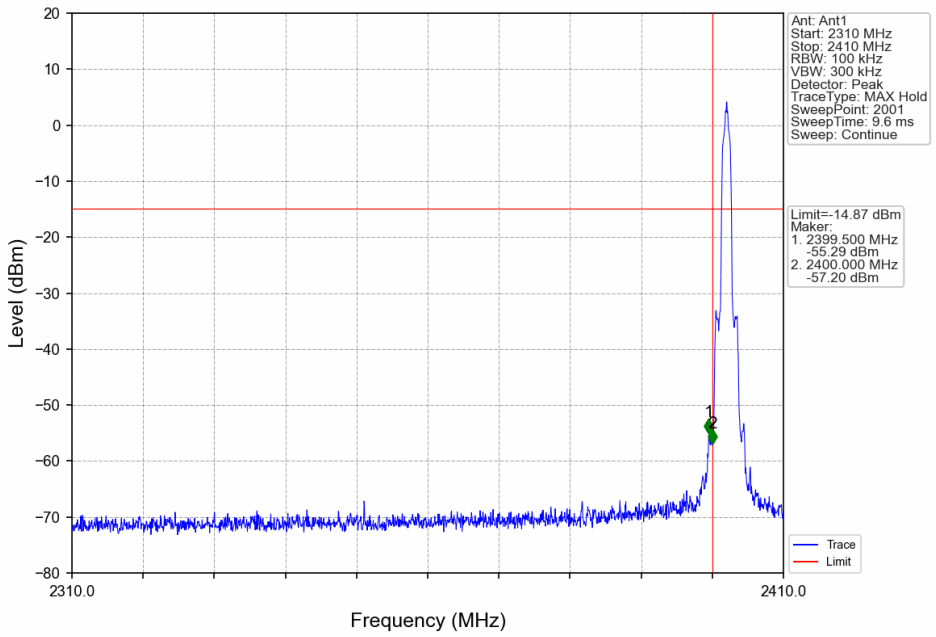
GFSK_DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



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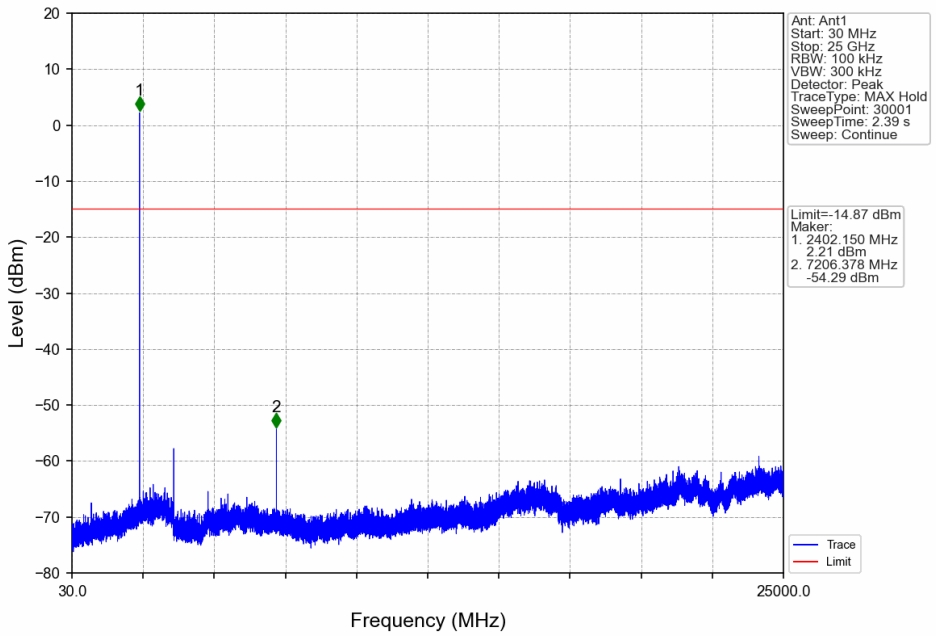
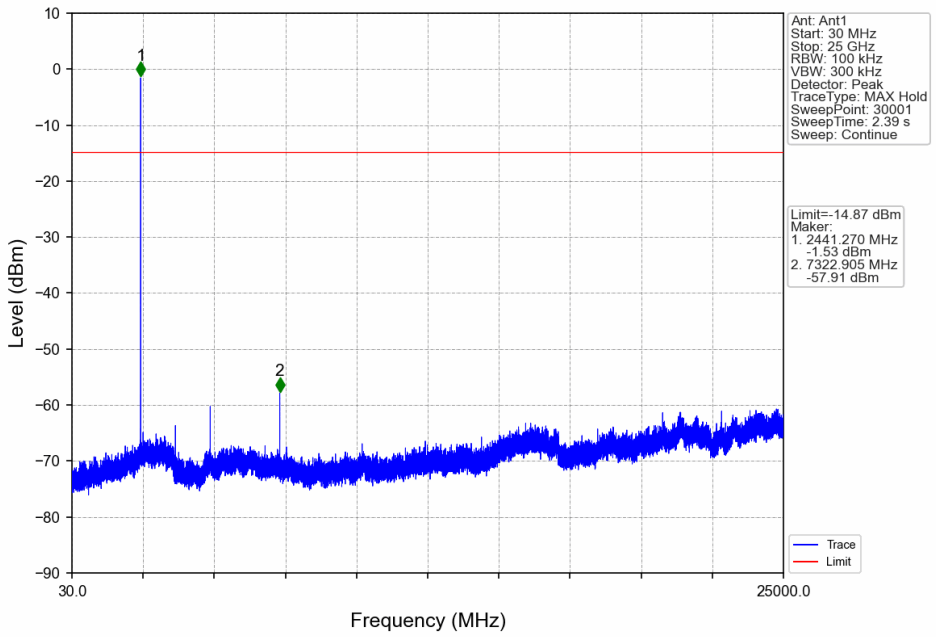
Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



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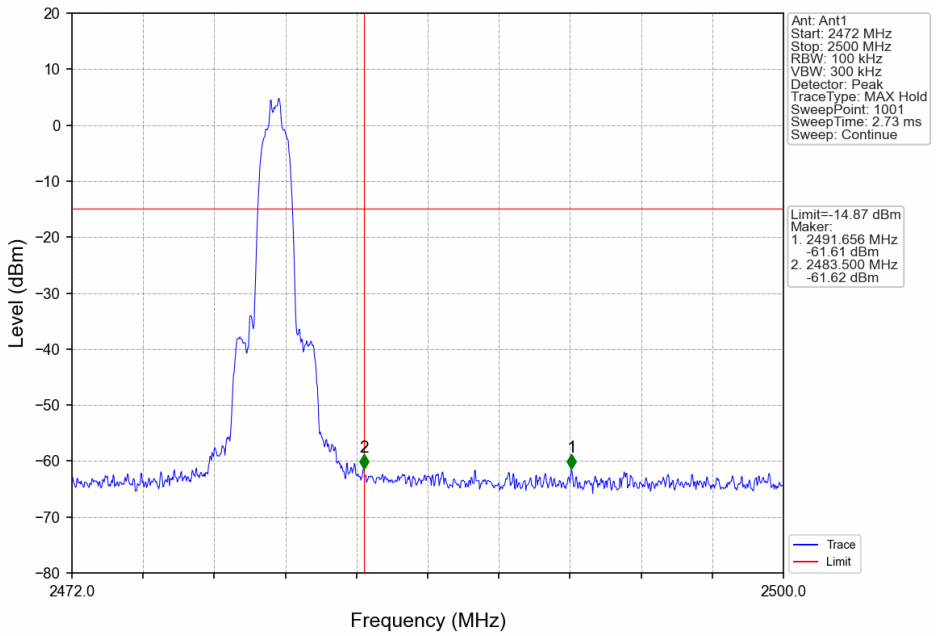
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



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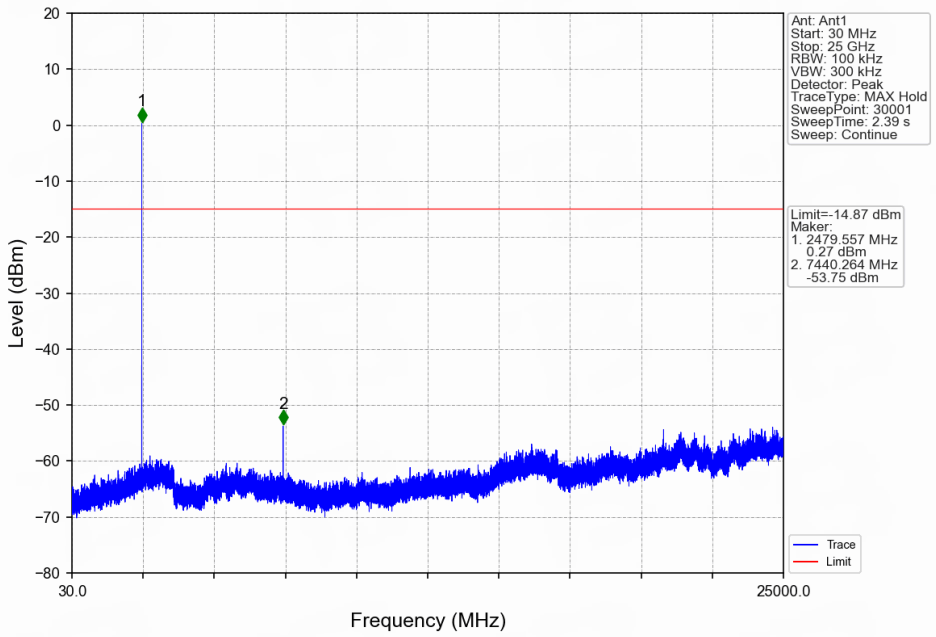

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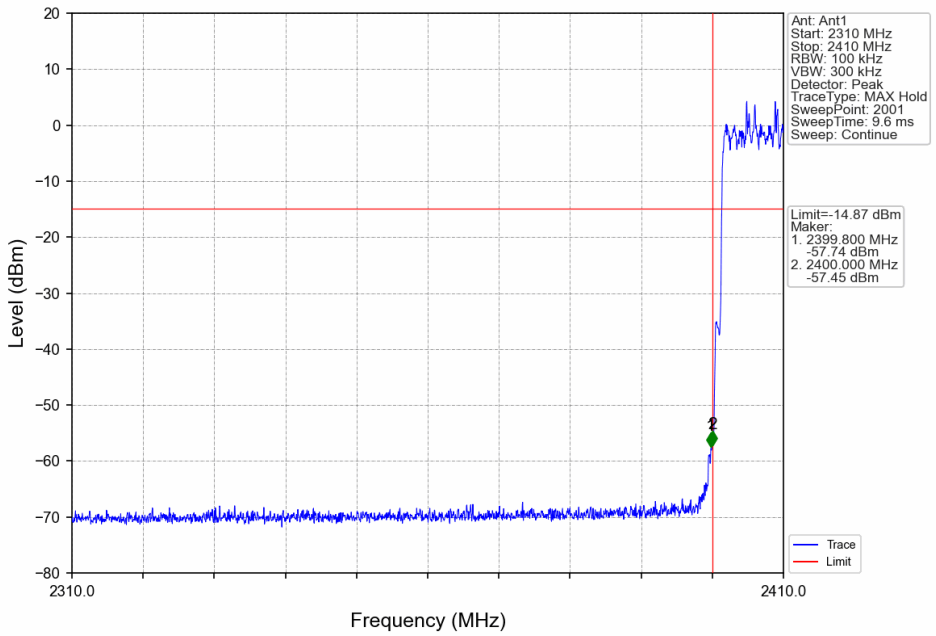
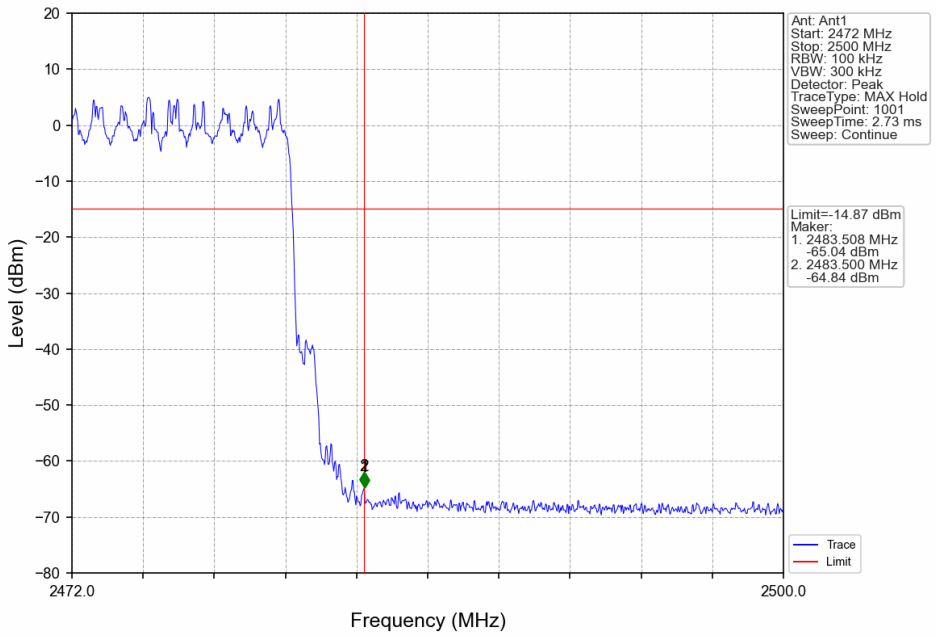
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



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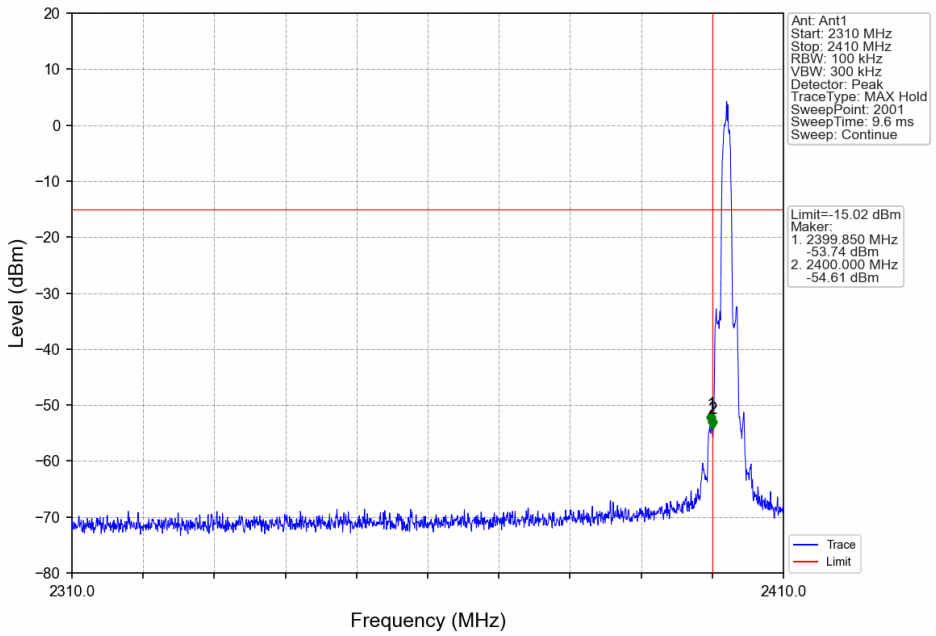
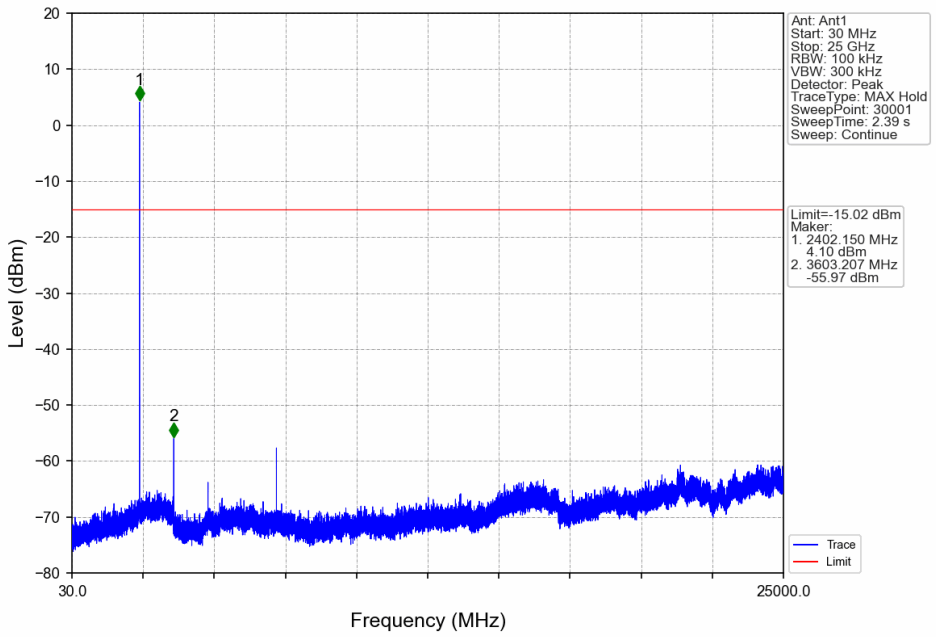
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



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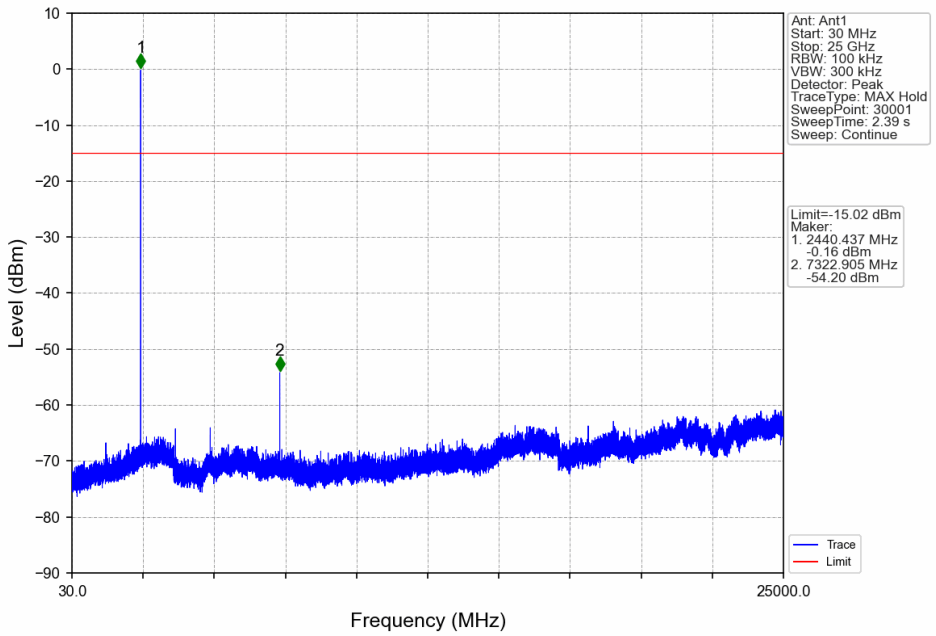
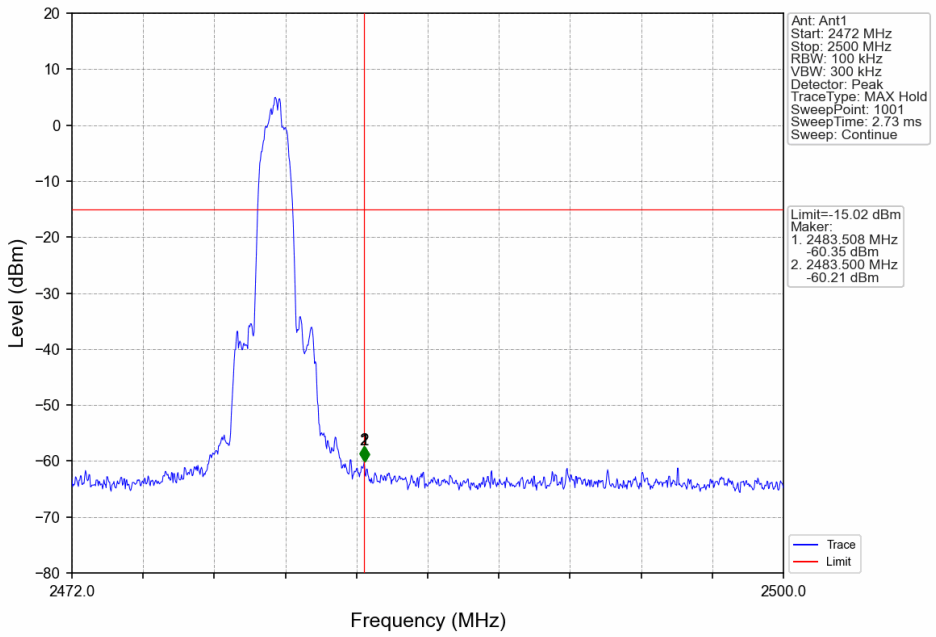
8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



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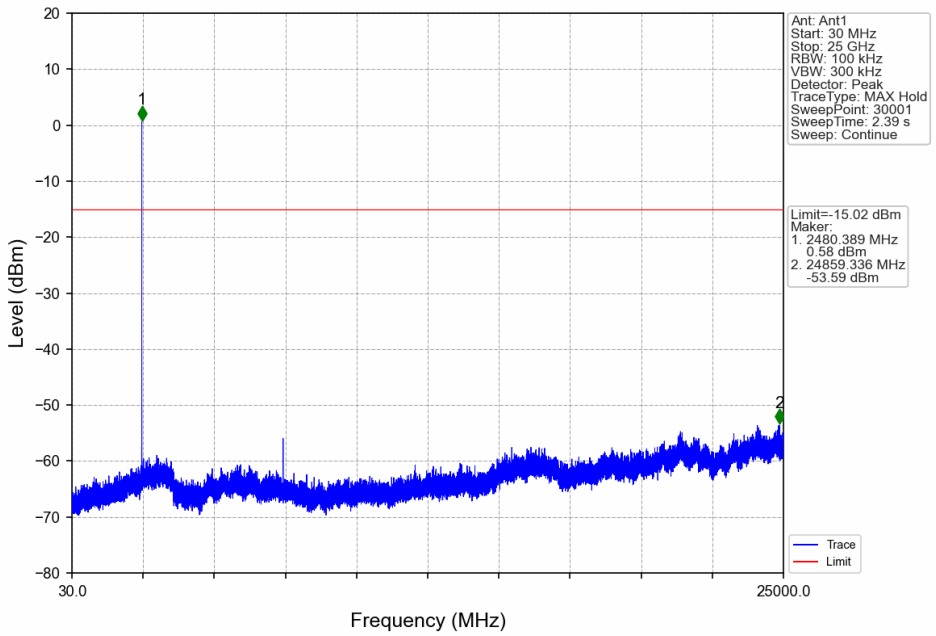
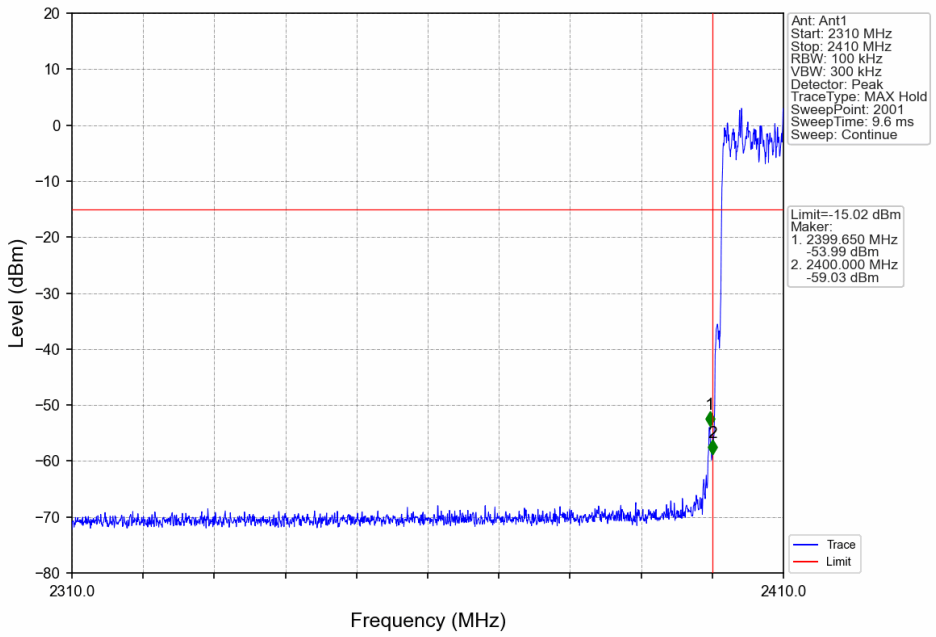
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



8DPSK_3DH5_HOPP_Ant1_NTNV



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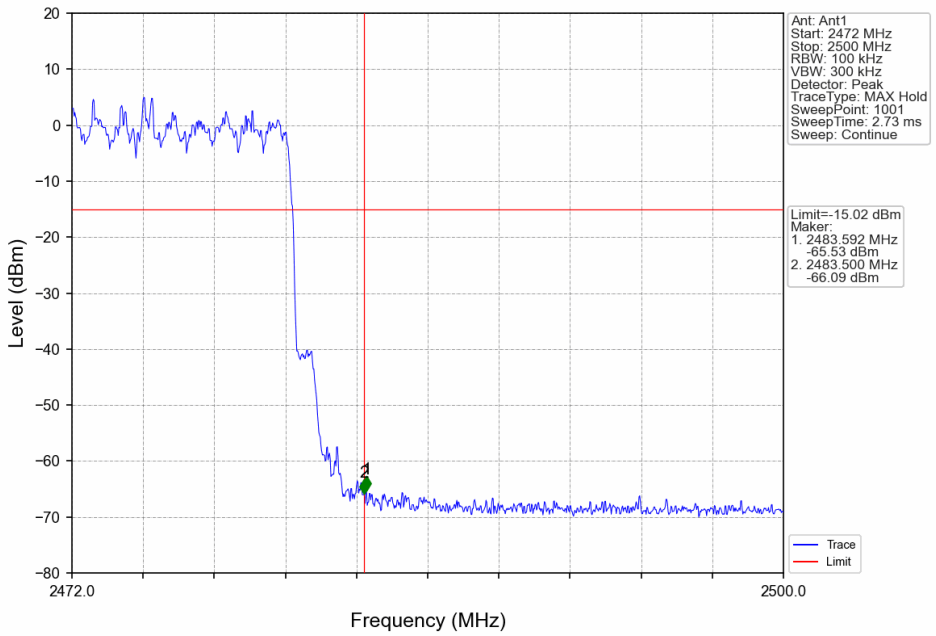
8DPSK_3DH5_HOPP_Ant1_NTNV



7. Form731

7.1 Form731

7.1.1 Test Result

Lower Freq (MHz)	High Freq (MHz)	MAX Power (W)	MAX Power (dBm)
2402	2480	0.0051	7.09

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